

# **EMC Test Report**

Report No.: AGC05443220333EE01

**PRODUCT DESIGNATION**: Wireless charging earbuds

**BRAND NAME** : N/A

MODEL NAME : M09768

**APPLICANT**: MID OCEAN BRANDS B.V

**DATE OF ISSUE** : Apr. 14, 2022

ETSI EN 301 489-1 V2.2.3 (2019-11)

**STANDARD(S)** : ETSI EN 301 489-3 V2.1.1 (2019-03)

ETSI EN 301 489-17 V3.2.4 (2020-09)

**REPORT VERSION**: V1.0

Attestation of Global Complian

(Shenzhen) Co., Ltd

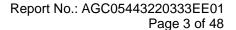




Page 2 of 48

## REPORT REVISE RECORD

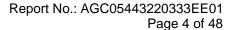
Report Version	Revise Time	Issued Date	Valid Version	Notes
V1.0	/	Apr. 14, 2022	Valid	Initial Release





#### **TABLE OF CONTENTS**

1. TEST REPORT CERTIFICATION	5
2. GENERAL INFORMATION	6
2.1. DESCRIPTION OF EUT	6
2.2. OBJECTIVE	_
2.3. TEST STANDARDS AND RESULTS	6
2.4. TEST ITEMS AND THE RESULTS	7
2.5. ENVIRONMENTAL CONDITIONS	7
3. TEST MODE DESCRIPTION	8
4. MEASUREMENT UNCERTAINTY	9
5. SUPPORT EQUIPMENT	_
6. IDENTIFICATION OF THE RESPONSIBLE TESTING LOCATION	11
7. RADIATED DISTURBANCE MEASUREMENT	
7.1. LIMITS OF RADIATED DISTURBANCES	_
7.2. TEST PROCEDURE	_
7.3. BLOCK DIAGRAM OF TEST SETUP	
7.4 TEST RESULT	
8. MAINS TERMINAL DISTURBANCE VOLTAGE MEASUREMENT	
8.1. LIMITS OF MAINS TERMINAL DISTURBANCE VOLTAGE	
8.2. TEST PROCEDURE	
8.3. TEST SETUP	
8.4. TEST RESULT	
9. HARMONIC CURRENT MEASUREMENT	_
9.1. LIMITS OF HARMONIC CURRENT	
9.2. TEST PROCEDURE	_
9.3. TEST SETUP	
9.4. TEST RESULT	
10. VOLTAGE FLUCTUATIONS AND FLICK MEASUREMENT	_
10.1. LIMITS OF VOLTAGE FLUCTUATIONS AND FLICK	
10.2. TEST PROCEDURE	
10.3. TEST SETUP	
10.4. TEST RESULT	
11. IMMUNITY TEST	_
11.1. DESCRIPTION OF PERFORMANCE CRITERIA	
11.2. GENERAL PERFORMANCE CRITERIA	
12. ELECTROSTATIC DISCHARGE IMMUNITY TEST	
12.1. TEST SPECIFICATION	
12.2. TEST PROCEDURE	
12.3. TEST SETUP	
12.4. TEST RESULT	
12.5. PERFORMANCE	
13. RADIATED, RADIO FREQUENCY ELECTROMAGNETIC FIELD IMMUNITY TEST	
13.1. TEST SPECIFICATION	32





13.2. TEST PROCEDURE	32
13.3. TEST SETUP	33
13.4. TEST RESULT	34
13.5. PERFORMANCE	34
14. ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST	35
14.1. TEST SPECIFICATION	35
14.2. TEST PROCEDURE	35
14.3. TEST SETUP	35
14.4. TEST RESULT	36
14.5. PERFORMANCE	36
15. SURGE IMMUNITY TEST	37
15.1. TEST SPECIFICATION	37
15.2. TEST PROCEDURE	37
15.3. TEST SETUP	37
15.4. TEST RESULT	38
15.5. PERFORMANCE	38
16. IMMUNITY TO CONDUCTED DISTURBANCES INDUCED BY RF FIELDS	39
16.1. TEST SPECIFICATION	39
16.2. TEST PROCEDURE	39
16.3. TEST SETUP	39
16.4. TEST RESULT	40
16.5. PERFORMANCE	40
17. VOLTAGE DIPS AND SHORT INTERRUPTIONS IMMUNITY TEST	41
17.1. TEST SPECIFICATION	41
17.2. TEST PROCEDURE	41
17.3. TEST SETUP	41
17.4. TEST RESULT	42
17.5. PERFORMANCE	
APPENDIX A: PHOTOGRAPHS OF TEST SETUP	43
APPENDIX B: PHOTOGRAPHS OF THE EUT	48



Page 5 of 48

## 1. TEST REPORT CERTIFICATION

II I LOI ILLI OILI OLI		
Applicant	MID OCEAN BRANDS B.V	
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong	
Manufacturer	MID OCEAN BRANDS B.V	
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong	
Factory	MID OCEAN BRANDS B.V	
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong	
Product Designation	Wireless charging earbuds	
Brand Name	N/A	
Test Model	MO9768	
Date of test	Mar. 31, 2022 to Apr. 12, 2022	
Deviation	None	
Condition of Test Sample Normal		
Test Result	Pass	
Report Template	AGCRT-EC-EMC	

The above equipment was tested by Attestation of Global Compliance (Shenzhen) Co., Ltd. for compliance with the requirements set forth in the Technical Standards mentioned above. The test record, data evaluation and test configuration represented herein are true and accurate accounts of measurements of the sample's EMC characteristics under the conditions herein specified.

The test results of this report relate only to the tested sample identified in this report

Prepared By	John Beng	
	John Zeng (Project Engineer)	Apr. 14, 2022
Reviewed By	Calin Lin	
	Calvin Liu (Reviewer)	Apr. 14, 2022
Approved By	Max Zhang	
	Max Zhang (Authorized Officer)	Apr. 14, 2022

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Report No.: AGC05443220333EE01 Page 6 of 48

## 2. GENERAL INFORMATION

#### 2.1. DESCRIPTION OF EUT

The EUT is a short range, Bluetooth device.

Details of technical specification refer to the description in follows:

Operating Frequency(BT)	2.402GHz to 2.480GHz
Operating Frequency(WPT)	110KHz-205KHz
Bluetooth Version	V5.0
Modulation(BT)	BR ⊠GFSK_1Mbps; EDR ⊠π /4-DQPSK_2Mbps ⊠8DPSK_3Mbps BLE □GFSK 1Mbps □GFSK 2Mbps
Modulation(WPT)	FSK
Number of Channels	79 Channels
Hardware Version	Bluetooth-AF0031 V1.0
Software Version	leader.1910.01 V5.0
Antenna Type(BT)	Ceramic Antenna
Antenna Type(WPT)	Coil Antenna
Antenna Gain	4dBi
Power Supply (Headset)	DC 3.7V by battery
Power Supply(Charging dock)	DC 3.7V by battery or DC 5V by adapter
Wireless Charging Output Power	5W(Max 5W)

#### 2.2. OBJECTIVE

Perform Electro Magnetic Interference (EMI) and Electro Magnetic Susceptibility (EMS) tests for CE Marking.

## 2.3. TEST STANDARDS AND RESULTS

The EUT has been tested according to ETSI EN 301 489-1 V2.2.3 (2019-11), ETSI EN 301 489-3 V2.1.1 (2019-03) and ETSI EN 301 489-17 V3.2.4 (2020-09).

ETSI EN 301 489-1	ElectroMagnetic Compatibility (EMC) standard for radio equipment and services; Part 1: Common technical requirements; Harmonised Standard for ElectroMagnetic Compatibility.
ETSI EN 301 489-3	Electro Magnetic Compatibility (EMC) standard for radio equipment and services; Part 3: Specific conditions for Short-Range Devices (SRD) operating on frequencies between 9 kHz and 246 GHz; Harmonised Standard covering the essential requirements of article 3.1(b) of Directive 2014/53/EU
ETSI EN 301 489-17	ElectroMagnetic Compatibility (EMC) standard for radio equipment and services; Part 17: Specific conditions for Broadband Data Transmission Systems; Harmonised Standard for ElectroMagnetic Compatibility



Page 7 of 48

#### 2.4. TEST ITEMS AND THE RESULTS

No.	Basic Standard	Test Type	Result	
EMIS	EMISSION (EN 301 489-1 §7.1)			
1	EN 55032	Radiated emission	PASS	
3	EN 55032	Conducted emission, AC ports	PASS	
4	EN 55032	Conducted emission, Telecom ports	N/A	
5	EN 61000-3-2	Harmonic current emissions	N/A	
6	EN 61000-3-3	Voltage fluctuations & flicker	PASS	
IMM	UNITY (EN 301 489-1	§7.2)		
7	EN 61000-4-2	Electrostatic discharge immunity	PASS	
8	EN 61000-4-3	Radiated RF electromagnetic field immunity	PASS	
9	EN 61000-4-4	Electrical fast transient/burst immunity	PASS	
10	ISO 7637-1, -2	Transients and surges, DC ports	N/A	
11	EN 61000-4-5	Surge immunity, AC ports, Telecom ports	PASS	
12	EN 61000-4-6	Immunity to conducted disturbances induced by RF fields	PASS	
13	EN 61000-4-11	Voltage dips and short interruptions immunity	PASS	

Note: 1. N/A- Not Applicable.

2. The latest versions of basic standards are applied.

## 2.5. ENVIRONMENTAL CONDITIONS

During the measurement the environmental conditions were within the listed ranges:

- Temperature: 15-35°C- Relative humidity: 30-60%

- Atmospheric pressure: 86-106kPa



Page 8 of 48

## 3. TEST MODE DESCRIPTION

NO.	TEST MODE DESCRIPTION	WORST	
1	Wireless Charging mode with adapter	V	
2	BT mode		
Note: 1. V means EMI worst mode.			
2. All modes have been tested and only the worst mode test data recorded in the test report.			

## I/O Port Information (⊠Applicable ☐Not Applicable)

I/O Port of EUT				
I/O Port Type	Number	Cable Description	Tested With	
Type-CPort(for charging dock)	1	0.3m unshielded	1	
Charging Port (for headset)	2		2	



Page 9 of 48

#### 4. MEASUREMENT UNCERTAINTY

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in measurement" (GUM) published by CISPR and ANSI.

- Uncertainty of Radiated Emission, Uc = ±2.9dB
- Uncertainty of Radiated Emission below 1GHz, Uc = ±3.8 dB
- Uncertainty of Radiated Emission above 1GHz, Uc = ±4.9 dB



Page 10 of 48

## 5. SUPPORT EQUIPMENT

Device Type	Manufacturer	Model	Serial No	Data Cable	Mains cable
Adapter	jinbaotong	K-T10E0502000E		-	DC 5V
Wireless charging pad		CP60		-	5W
Mobile phone	Xiaomi	Mi 10			

Note: 1. "-- "means no any support device during testing.



Page 11 of 48

## 6. IDENTIFICATION OF THE RESPONSIBLE TESTING LOCATION

Site	Attestation of Global Compliance (Shenzhen) Co., Ltd
Location	1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China

#### TEST EQUIPMENT OF CONDUCTED EMISSION TEST

Equipment Manufacturer		Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESPI	101206	Mar.28, 2022	Mar.27, 2023
Artificial power network	R&S	ESH2-Z5	100086	Jun. 09, 2021	Jun. 08, 2022
Test Software	FARA	EZ-EMC(Ver. AGC-CON03A1)	N/A	N/A	N/A

#### **TEST EQUIPMENT OF RADIATED EMISSION TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESCI	100034	Sep. 06, 2021	Sep. 05, 2022
Wideband Antenna	SCHWARZBEC K	VULB9168	D69250	Apr. 28, 2021	Apr. 27, 2023
Double-Ridged Waveguide Horn	ETS	3117	00154520	Sep. 06, 2021	Sep. 05, 2023
Preamplifier Assembly	ETS	3117PA	00225134	Sep. 03, 2020	Sep. 02, 2022
EXA Signal Analyzer	Aglient	N9010A	MY53470504	Nov. 17, 2021	Nov. 16, 2022
Test software	FARA	EZ-EMC (Ver.RA-03A)	N/A	N/A	N/A
Test Software	Tonscend	JS32-RE(Ver.2.5)	N/A	N/A	N/A

#### TEST EQUIPMENT OF POWER HARMONICS / VOLTAGE FLUCTUATION / FLICKER TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Conditioning Unit	Schaffner	CCN1000-1	72431	Jul. 19, 2021	Jul. 18, 2022
AC Source	Schaffner	NSG1007	56825	Jul. 19, 2021	Jul. 18, 2022

## **TEST EQUIPMENT OF ESD TEST**

Equipment	Equipment Manufacturer		S/N	Cal. Date	Cal. Due	
ESD Simulator	Schaffner	NSG 438	782	Jan. 03, 2022	Jan. 02, 2023	



Page 12 of 48

#### **TEST EQUIPMENT OF RS IMMUNITY TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Generator	KEYSIGHT	N5182A	N5182A	Mar. 04, 2022	Mar.03, 2023
Power Probe	R&S	URV5-Z4	100124	Apr. 26, 2021	Apr. 25, 2023
Power Meter	R&S	NRVD	8323781027	Apr. 26, 2021	Apr. 25, 2023
Power Amplifier	L2	S2006-0001	BPA00T10W5 00-1	N/A	N/A
Power Amplifier	Milmega	AS0104-55_55	1004793	N/A	N/A
Power Amplifier	Rflight	NTWPA-2560100	17063183	N/A	N/A
Broadband High Gain Horn Antenna	SCHWARZBEC K	BBHA 9120 J	00073	N/A	N/A
Double-Ridged Waveguide Horn	ETS LINDGREN	3117	00034609	Apr. 23, 2021	Apr. 22, 2023
Wideband Antenna	SCHWARZBEC K	VULB9168	D69250	Apr. 28, 2021	Apr. 27, 2023

## **EST EQUIPMENT OF SURGE/EFT/DIPS TEST**

Equipment Manufacturer		Model S/N		Cal. Date	Cal. Due	
EFT/Surge Generator	Schaffner	Modula 6150	34437	Jul. 19, 2021	Jul. 18, 2022	

## **EST EQUIPMENT OF CS IMMUNITY TEST**

Equipment Manufacturer		Model	S/N	Cal. Date	Cal. Due
Power Amplifier	AR	75A250	18464	N/A	N/A
CDN	ZHINAN	ZN3751	15004	Sep. 03, 2020	Sep. 02, 2022
6dB attenuator	ZHINAN	E-002	N/A	Sep. 03, 2020	Sep. 02, 2022
Power Probe	R&S	URV5-Z4	100124	Apr. 26, 2021	Apr. 25, 2023
Electromagnetic Injection Clamp	Luthi	EM101	35773	Aug. 25, 2020	Aug. 24, 2022
Power Meter	R&S	NRVD	8323781027	Apr. 26, 2021	Apr. 25, 2023
Signal Generator	Aglient	E4421B	MY43351603	Mar. 04, 2022	Mar.03, 2023



Page 13 of 48

## 7. RADIATED DISTURBANCE MEASUREMENT

#### 7.1. LIMITS OF RADIATED DISTURBANCES

Limits for radiated disturbance 30M to1 GHz at a measurement distance of 3 m

Frequency range (MHz)	Quasi peak limits(dBuV/m), for Class B ITE, at 3m measurement distance
30-230	40
230-1000	47

## Limits for radiated disturbance above 1 GHz at a measurement distance of 3 m

Eroguenov rongo (MUT)	Limits (dBu\	//m), Class B ITE
Frequency range (MHz)	Peak	Average
1000-3000	70	50
3000-6000	74	54

Note: 1. The lower limit shall apply at the transition frequency.

2. Additional provisions may be required for cases where interference occurs.

#### 7.2. TEST PROCEDURE

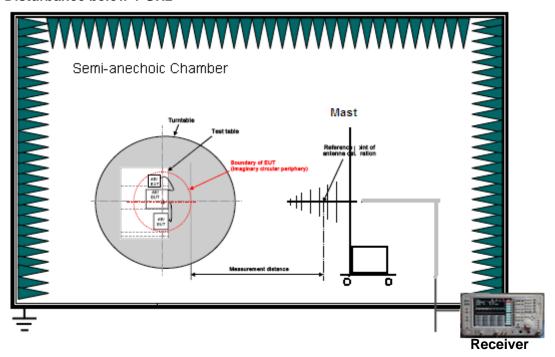
- (1). The EUT was placed on the top of an insulating table 0.8 meters above the ground at a semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- (2). The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- (3). The antenna is a broadband antenna, and its height is varied from 1 to 4 meter above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- (4). For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to the heights from 1 to 4 meters and the ratable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- (5). The test-receiver system was set to Peak Detector Function and Specified Bandwidth with Maximum Hold Mode. If the emission level of the EUT in peak mode was 10dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emission that did not have 10dB margin would be retested one by one using the quasi-peak method.



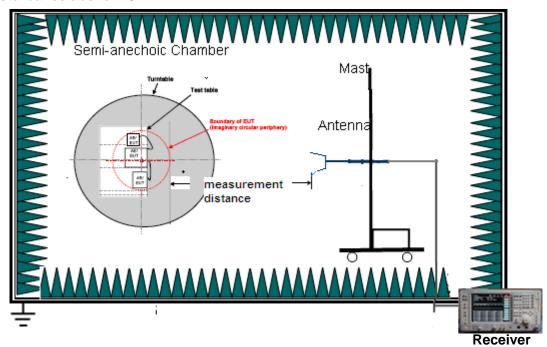
#### 7.3. BLOCK DIAGRAM OF TEST SETUP

System Diagram of Connections between EUT and Simulators

#### **Radiated Disturbance below 1 GHz**



#### Radiated Disturbance above 1 GHz



For the actual test configuration, please refer to the related item – Photographs of the Test Configuration.

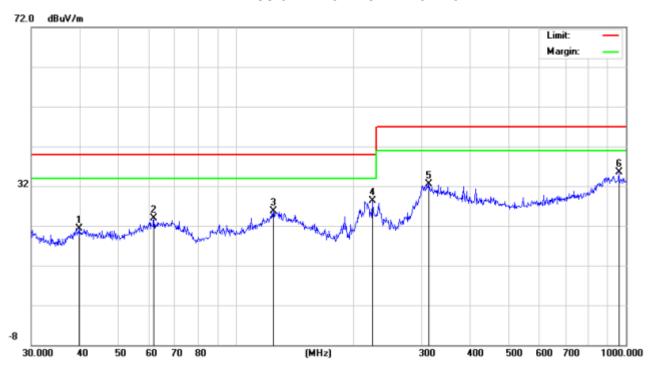


#### 7.4 TEST RESULT

The test modes were carried out for all modes.

The worst test mode of the EUT was Mode 1, and its test data was showed as the follow:

#### RADIATED EMISSION BELOW 1GHZ-HORIZONTAL

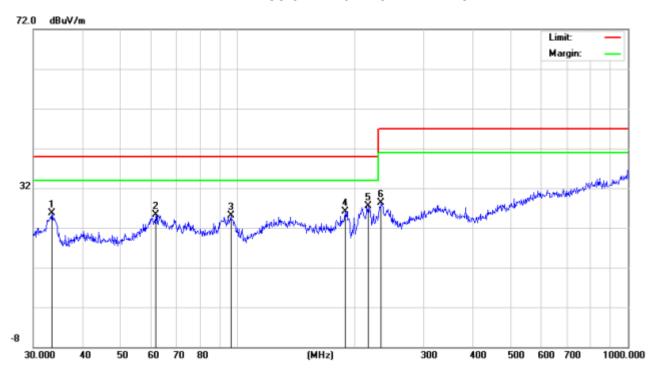


No.	Mk	. Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector
1		39.7146	5.41	15.93	21.34	40.00	-18.66	peak
2		61.7781	6.30	17.59	23.89	40.00	-16.11	peak
3		125.0066	6.89	18.89	25.78	40.00	-14.22	peak
4		224.5193	10.22	18.11	28.33	40.00	-11.67	peak
5		313.2760	8.14	24.34	32.48	47.00	-14.52	peak
6	*	958.7943	6.55	28.92	35.47	47.00	-11.53	peak

**RESULT: PASS** 

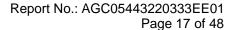


#### RADIATED EMISSION BELOW 1GHZ- VERTICAL



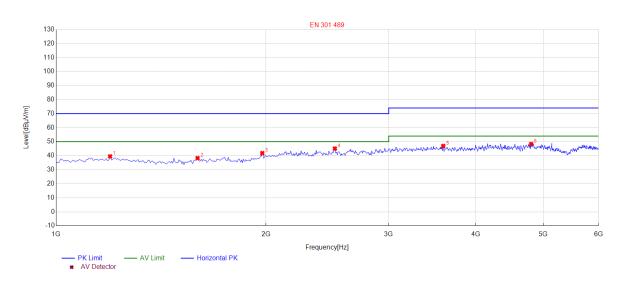
No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector
1		33.4448	12.40	13.27	25.67	40.00	-14.33	peak
2		61.7781	7.48	17.91	25.39	40.00	-14.61	peak
3		96.0986	10.30	14.78	25.08	40.00	-14.92	peak
4		188.4124	9.77	16.42	26.19	40.00	-13.81	peak
5	*	216.0240	11.74	15.81	27.55	40.00	-12.45	peak
6		233.3487	9.88	18.52	28.40	47.00	-18.60	peak

**RESULT: PASS** 



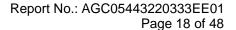


#### RADIATED EMISSION ABOVE 1GHZ-HORIZONTAL



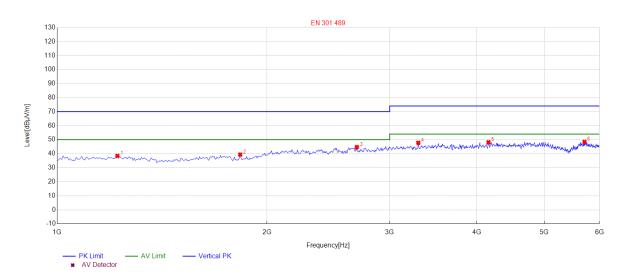
NO.	Freq. [MHz]	Level [dBµV/m]	Factor [dB]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle [°]	Polarity
1	1195.1952	39.51	-16.83	70.00	30.49	100	180	Horizontal
2	1595.5956	38.25	-16.11	70.00	31.75	100	230	Horizontal
3	1975.976	41.85	-12.08	70.00	28.15	100	230	Horizontal
4	2511.5115	45.11	-9.71	70.00	24.89	100	300	Horizontal
5	3592.5926	46.94	-7.40	74.00	27.06	100	320	Horizontal
6	4803.8038	48.35	-4.91	74.00	25.65	100	250	Horizontal

**RESULT: PASS** 





#### RADIATED EMISSION ABOVE 1GHZ- VERTICAL



NO.	Freq.	Level	Factor	Limit	Margin	Height	Angle	Polarity
140.	[MHz]	[dBµV/m]	[dB]	[dBµV/m]	[dB]	[cm]	[°]	1 Granty
1	1220.2202	38.41	-16.86	70.00	31.59	100	70	Vertical
2	1830.8308	39.39	-13.62	70.00	30.61	100	50	Vertical
3	2691.6917	44.75	-9.57	70.00	25.25	100	10	Vertical
4	3297.2973	47.79	-8.30	74.00	26.21	100	20	Vertical
5	4158.1582	48.16	-6.09	74.00	25.84	100	140	Vertical
6	5709.7097	48.42	-4.62	74.00	25.58	100	160	Vertical

**RESULT: PASS** 



Page 19 of 48

#### 8. MAINS TERMINAL DISTURBANCE VOLTAGE MEASUREMENT

#### 8.1. LIMITS OF MAINS TERMINAL DISTURBANCE VOLTAGE

Fraguency range (MHz)	Limits (dBuV) Class B ITE		
Frequency range (MHz)	Quasi-peak	Average	
0.15-0.50	66 to 56	56 to 46	
0.50-5	56	46	
5-30	60	50	

Note: 1. The lower limit shall apply at the transition frequencies.

2. The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50MHz.

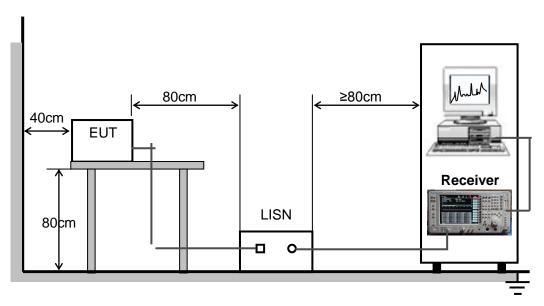
#### **8.2. TEST PROCEDURE**

- (1) The EUT was placed 0.4 meters from the conducting wall of shielded room with EUT being connected to the power mains through a line impedance stabilization network (LISN). The LISN provide  $50\Omega/50\mu H$  of coupling impedance for the measuring instrument.
- (2) Both lines of the power mains connected to the EUT were checked for maximum conducted interference.
- (3)The frequency range from 150 kHz to 30 MHz was searched. Emission levels over 20dB under the prescribed limits are not reported.





#### 8.3. TEST SETUP



For the actual test configuration, please refer to the related item - Photographs of the Test Configuration.

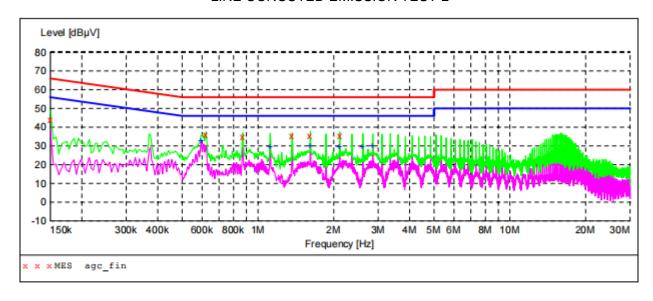


## 8.4. TEST RESULT

The test modes were carried out for all modes.

The worst test mode of the EUT was Mode 1, and its test data was showed as the follow:

#### LINE CONCUTED EMISSION TEST-L



## MEASUREMENT RESULT: "agc\_fin"

2022/4/2 22:24 Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000 0.622000 0.870000 1.366000 1.614000 2.114000	43.80 36.10 34.90 35.40 35.60 35.20	6.9 5.4 5.4 5.9 6.2 6.5	66 56 56 56 56	22.2 19.9 21.1 20.6 20.4 20.8	QP QP QP QP QP QP	L1 L1 L1 L1 L1	GND GND GND GND GND GND

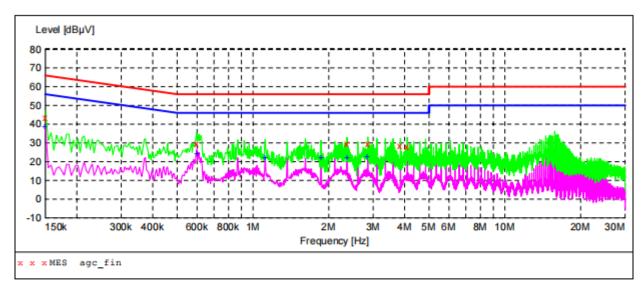
## MEASUREMENT RESULT: "agc\_fin2"

1.118000 29.70 5.6 46 16.3 AV L1 GND 1.614000 30.10 6.2 46 15.9 AV L1 GND 2.114000 29.50 6.5 46 16.5 AV L1 GND	2022/4/2 22:2 Frequency MHz	4 Level dBμV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
	1.118000 1.614000 2.114000 2.610000	29.70 30.10 29.50 29.70	5.6 6.2 6.5 6.5	46 46 46 46	16.3 15.9 16.5 16.3	AV AV AV	L1 L1 L1	GND GND GND GND GND

**RESULT: PASS** 



#### LINE CONCUTED EMISSION TEST-N



## MEASUREMENT RESULT: "agc fin"

2022/4/2 22:21 Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000 0.598000 2.362000 2.858000 3.850000 4.098000	43.50 29.70 29.40 29.80 28.50 28.10	6.9 5.4 6.5 6.5 6.5	66 56 56 56 56	22.5 26.3 26.6 26.2 27.5 27.9	QP QP QP QP QP QP	N N N N N	GND GND GND GND GND GND

## MEASUREMENT RESULT: "agc\_fin2"

2022/4/2 22:21 Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000	38.60	6.9	56	17.4	AV	N	GND
0.598000	24.30	5.4	46	21.7	AV	N	GND
1.118000	21.90	5.6	46	24.1	AV	N	GND
1.862000	21.90	6.4	46	24.1	AV	N	GND
2.362000	22.00	6.5	46	24.0	AV	N	GND
2.858000	22.60	6.5	46	23.4	AV	N	GND

**RESULT: PASS** 



Page 23 of 48

#### 9. HARMONIC CURRENT MEASUREMENT

#### 9.1. LIMITS OF HARMONIC CURRENT

Limits for	Limits for Class A Equipment				
Harmonics Order n	Max. permissible harmonic current (A)				
Od	d harmonics				
3	2.30				
5	1.14				
7	0.77				
9	0.40				
11	0.33				
13	0.21				
15≤n≤39	0.15×15/n				
Eve	n harmonics				
2	1.08				
4	0.43				
6	0.30				
8≤n≤40	0.23×8/n				

Note: 1. According to section 5 of EN 61000-3-2: 2014, the EUT is Class A equipment.

2. The above limits are for all applications having an active input power>75W. No limits apply for equipment with an active input power up to and including 75W.

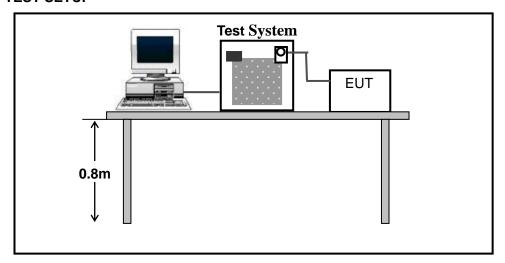
#### 9.2. TEST PROCEDURE

- 1. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- 2. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the necessary for the EUT to be exercised.



Page 24 of 48

#### 9.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.

## 9.4. TEST RESULT

Note: No applicable for equipment with an active input power up to and including 75W.



Page 25 of 48

#### 10. VOLTAGE FLUCTUATIONS AND FLICK MEASUREMENT

## 10.1. LIMITS OF VOLTAGE FLUCTUATIONS AND FLICK

Test Item	Limit	Note
P <sub>st</sub>	1.0	P <sub>st</sub> means Short-term flicker indicator
P <sub>lt</sub>	0.65	P <sub>lt</sub> means long-term flicker indicator
T <sub>dt</sub>	0.5	T <sub>dt</sub> means maximum time that d <sub>t</sub> exceeds 3.3%
d <sub>max</sub> (%)	4%	d <sub>max</sub> means maximum relative voltage change.
d <sub>c</sub> (%)	3.3%	d <sub>c</sub> means relative steady-state voltage change.

#### **10.2. TEST PROCEDURE**

- 1. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal conditions
- 2. During the flick measurement, the measure time shall include that part of whole operation changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

#### 10.3. TEST SETUP

Same as 9.3

#### 10.4. TEST RESULT

## **Test Specification**

Test Frequency	50Hz	Test Voltage	230V AC
Waveform	Sine	Test Time	10 minutes(P <sub>st</sub> ); 2 hours (P <sub>lt</sub> )

#### **Test Result**

Test Parameter	Measurement Value	Limit	Remarks
P <sub>st</sub>	0.160	1.0	Pass
P <sub>It</sub>	0.070	0.65	Pass
T <sub>dt(s)</sub>	0.0	0.5	Pass
d <sub>max</sub> (%)	0.00%	4%	Pass
d <sub>c</sub> (%)	0.00%	3.3%	Pass



Page 26 of 48

#### 11. IMMUNITY TEST

#### 11.1. DESCRIPTION OF PERFORMANCE CRITERIA

The performance criteria are used to take a decision on whether a radio equipment passes or fails immunity tests.

For the purpose of the present document two categories of performance criteria apply:

- Performance criteria for continuous phenomena.
- Performance criteria for transient phenomena.

#### 11.2. GENERAL PERFORMANCE CRITERIA

#### 1. Performance criteria for continuous phenomena

During the test, the equipment shall:

- · continue to operate as intended;
- not unintentionally transmit;
- not unintentionally change its operating state;
- not unintentionally change critical stored data.

#### 2. Performance criteria for transient phenomena

For all ports and transient phenomena with the exception described below, the following applies:

- The application of the transient phenomena shall not result in a change of the mode of operation (e.g. unintended transmission) or the loss of critical stored data.
- After application of the transient phenomena, the equipment shall operate as intended.

For surges applied to symmetrically operated wired network ports intended to be connected directly to outdoor lines the following criteria applies:

- For products with only one symmetrical port intended for connection to outdoor lines, loss of function is allowed, provided the function is self-recoverable, or can be otherwise restored. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.
- For products with more than one symmetrical port intended for connection to outdoor lines, loss of function on the port under test is allowed, provided the function is self-recoverable. Information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

For a 0 % residual voltage dip tests the following performance criteria apply:

The performance criteria for transient phenomena shall apply.

For a 70 % residual voltage dip and voltage interruption tests, the following performance criteria apply:

- in the case where the equipment is fitted with or connected to a battery back-up, the performance criteria for transient phenomena shall apply;
- in the case where the equipment is powered solely from the AC mains supply (without the use of a parallel battery back-up) volatile user data may have been lost and if applicable the communication link need not to be maintained and lost functions should be recoverable by user or operator;
- no unintentional responses shall occur at the end of the test, when the voltage is restored to nominal;
- in the event of loss of function(s) or in the event of loss of user stored data, this fact shall be recorded.



Page 27 of 48

#### 3. Performance Table

	EN 301 489-3 Performance criteria					
Criteria	During Test	After Test				
А	Operate as intended No loss of function No unintentional responses	Operate as intended No loss of function No degradation of performance No loss of stored data or user programmable functions				
В	May show loss of function No unintentional responses	Operate as intended Lost function(s) shall be self-recoverable No degradation of performance No loss of stored data or user programmable functions				

- performance criterion A applies for immunity tests with phenomena of a continuous nature;
- performance criterion B applies for immunity tests with phenomena of a transient nature.

Where "operate as intended" or "no loss of function" is specified, the EUT shall demonstrate correct functioning as described in EN 301 489-3 clause 5.

Where the EUT has more than one mode of operation, an unplanned transition from one mode to another is considered as an unintentional response. The EUT shall be tested in sufficient modes to confirm there are no such unintentional responses.

	EN 301 489-17 Performance criteria					
Criteria	During Test	After Test (i.e. as a result of the application of the test)				
А	Shall operate as intended. (see note). Shall be no loss of function. Shall be no unintentional transmissions.	Shall operate as intended. Shall be no degradation of performance. Shall be no loss of function. Shall be no loss of critical stored data.				
В	May be loss of function.	Functions shall be self-recoverable. Shall operate as intended after recovering. Shall be no loss of critical stored data.				
С	May be loss of function.	Functions shall be recoverable by the operator. Shall operate as intended after recovering. Shall be no loss of critical stored data.				

The performance criteria A shall apply for continuous phenomena.

The performance criteria B shall apply for transient phenomena, except for voltage dips greater than or equal to 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply. Where the EUT is a transmitter in standby mode or receive mode, unintentional transmission shall not occur during the test.

Note: Operate as intended during the test allows a level of degradation in accordance with the Minimum performance level.

#### Minimum performance level

For equipment that supports a PER or FER, the minimum performance level shall be a PER or FER less than or equal to 10 %.

For equipment that does not support a PER or a FER, the minimum performance level shall be no loss of the wireless transmission function needed for the intended use of the equipment.



Page 28 of 48

#### 12. ELECTROSTATIC DISCHARGE IMMUNITY TEST

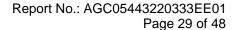
#### 12.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-2		
Discharge Impedance	330Ω/150 pF		
Discharge Voltage	ir Discharge:8kV, Contact Discharge:4kV		
Polarity	Positive/Negative		
Number of Discharge	Minimum 20 times at each test point		
Discharge Mode	Single discharge		
Discharge Period	1-second minimum		

#### 12.2. TEST PROCEDURE

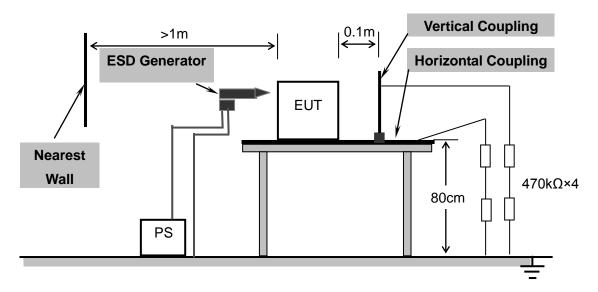
The test procedure was in accordance with EN 61000-4-2:

- a. Electrostatic discharges were applied only to those points and surfaces of the EUT that are accessible to users during normal operation.
- b. The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.
- c. The time interval between two successive single discharges was at least 1 second.
- d. The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the EUT.
- e. Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.
- f. Air discharges were applied with the round discharge tip of the discharge electrode approaching the EUT as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator was removed from the EUT and re-triggered for a new single discharge. The test was repeated until all discharges were completed.
- g. At least ten single discharges (in the most sensitive polarity) were applied to the Horizontal Coupling Plane at points on each side of the EUT. The ESD generator was positioned vertically at a distance of 0.1 meters from the EUT with the discharge electrode touching the HCP.
- h. At least ten single discharges (in the most sensitive polarity) were applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four faces of the EUT were completely illuminated. The VCP (dimensions 0.5mx0.5m) was placed vertically to and 0.1 meters from the EUT.





#### 12.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.

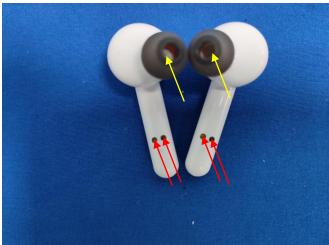


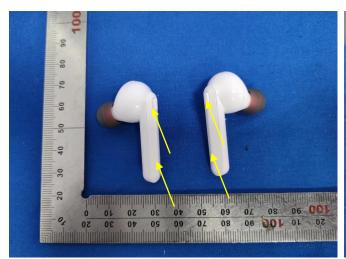
Page 30 of 48

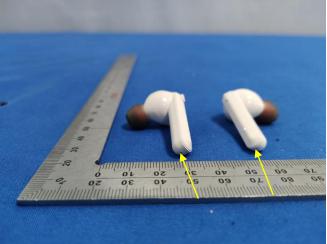
#### **ESD** location:

Yellow line: Air discharge Red line: Contact discharge











Page 31 of 48

#### 12.4. TEST RESULT

Voltage	Coupling	Test Mode	Performance criteria
±2kV; ±4kV	Contact discharge	Mode 1/2	А
±2kV; ±4kV; ±8kV	Air Discharge	Mode 1/2	А
±4kV	Indirect Discharge HCP	Mode 1/2	А
±4kV	Indirect Discharge VCP	Mode 1/2	А
	±2kV; ±4kV ±2kV; ±4kV; ±8kV ±4kV	±2kV; ±4kV Contact discharge  ±2kV; ±4kV; ±8kV Air Discharge  ±4kV Indirect Discharge HCP	±2kV; ±4kV Contact discharge Mode 1/2  ±2kV; ±4kV; ±8kV Air Discharge Mode 1/2  ±4kV Indirect Discharge HCP Mode 1/2

A: No degradation in the performance of the EUT was observed.

## 12.5. PERFORMANCE

⊠Criteria A:	function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.		
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.		
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.		

The apparatus continues to operate as intended. No degradation of performance or loss of



Page 32 of 48

# 13. RADIATED, RADIO FREQUENCY ELECTROMAGNETIC FIELD IMMUNITY TEST

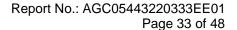
## 13.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-3		
Frequency Range	80MHz-6000MHz		
Field Strength	3V/m		
Modulation	1 kHz sine wave, 80%, AM modulation		
Frequency Step	1% of fundamental		
Polarity of Antenna	Horizontal and Vertical		
Test Distance	3m		
Antenna Height	1.55m		
Dwell Time	3 seconds		

#### 13.2. TEST PROCEDURE

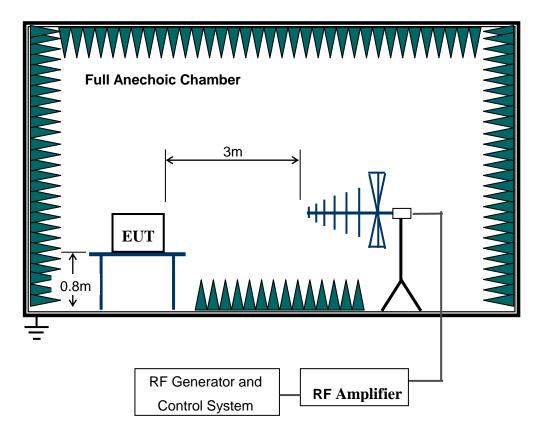
The test procedure was in accordance with EN 61000-4-3.

- a. The testing was performed in a fully anechoic chamber. The transmit antenna was located at a distance of 3 meters from the EUT.
- b. The test signal was 80% amplitude modulated with a 1 kHz sine wave.
- c. The frequency range was swept from 80 MHz to 6000MHz with the exception of the exclusion band for transmitters, receivers and duplex transceivers. The rate of sweep did not exceed 1.5×10<sup>-3</sup> decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- d. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- e. The field strength level was 3V/m.
- f. The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.





#### 13.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 34 of 48

#### 13.4. TEST RESULT

Field	Modulation	Polarity	Position	Test Mode	Performance criteria
3V/m	Yes	Н	Front	Mode 1/2	Α
3V/m	Yes	Н	Back	Mode 1/2	А
3V/m	Yes	Н	Left	Mode 1/2	А
3V/m	Yes	Н	Right	Mode 1/2	А
3V/m	Yes	V	Front	Mode 1/2	А
3V/m	Yes	V	Back	Mode 1/2	А
3V/m	Yes	V	Left	Mode 1/2	А
3V/m	Yes	V	Right	Mode 1/2	А
	3V/m 3V/m 3V/m 3V/m 3V/m 3V/m	3V/m       Yes         3V/m       Yes	3V/m       Yes       H         3V/m       Yes       H         3V/m       Yes       H         3V/m       Yes       H         3V/m       Yes       V         3V/m       Yes       V         3V/m       Yes       V         3V/m       Yes       V	3V/m         Yes         H         Front           3V/m         Yes         H         Back           3V/m         Yes         H         Left           3V/m         Yes         H         Right           3V/m         Yes         V         Front           3V/m         Yes         V         Back           3V/m         Yes         V         Left	3V/m         Yes         H         Front         Mode 1/2           3V/m         Yes         H         Back         Mode 1/2           3V/m         Yes         H         Left         Mode 1/2           3V/m         Yes         H         Right         Mode 1/2           3V/m         Yes         V         Front         Mode 1/2           3V/m         Yes         V         Back         Mode 1/2           3V/m         Yes         V         Left         Mode 1/2

A: No degradation or PER < 10% in the performance of the EUT was observed.

## 13.5. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
□Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
⊠ Compliance	☐ Not Compliance



Page 35 of 48

#### 14. ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST

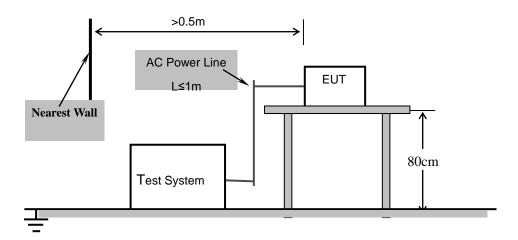
#### 14.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-4		
Test Voltage	a.c. power port–1kV		
Polarity	Positive/Negative		
Impulse Frequency	5kHz		
Impulse wave shape	5/50ns		
<b>Burst Duration</b>	15ms		
Burst Period	300ms		
Test Duration	Not less than 1min.		

#### 14.2. TEST PROCEDURE

- 1. The EUT was tested with 1000 volt discharges to the AC power input leads.
- 2. Both positive and negative polarity discharges were applied.
- 3. The length of the "hot wire" from the coaxial output of the EFT generator to the terminals on the EUT should not exceed 1 meter.
- 4. The duration time of each test sequential was 1 minute.
- 5. The transient/burst waveform was in accordance with IEC 61000-4-4, 5/50ns.

#### 14.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 36 of 48

#### 14.4. TEST RESULT

Test Point	Polarity	Test Level (kV)	Test Mode	Performance criteria
a.c. port, L	+/-	1	Mode 1	Α
a.c. port, N	+/-	1	Mode 1	А
a.c. port, L-N	+/-	1	Mode 1	А
a.c. port, L-N	+/-	1	Mode 1	А
	+/-	1		

A: No degradation in the performance of the EUT was observed.

## 14.5. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
	☐ Not Compliance

|--|--|



Page 37 of 48

#### 15. SURGE IMMUNITY TEST

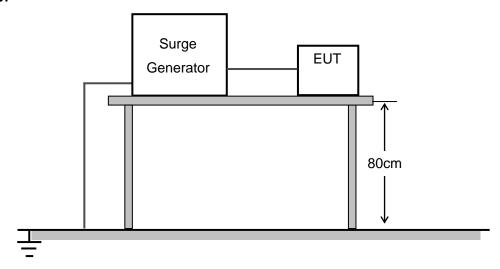
#### 15.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-5
Waveform	Voltage 1.2/50μs; Current 8/20μs
Test Voltage a.c. power port, line to line 1.0kV	
Polarity Positive/Negative	
<b>Phase Angle</b> 0°, 90°, 180°, 270°	
Repetition Rate	60sec
Times 5 time/each condition.	

#### 15.2. TEST PROCEDURE

- a. The EUT and the auxiliary equipment were placed on a table of 0.8m heights above a metal ground reference plane. The size of ground plane is greater than 1m×1m and project beyond the EUT by at least 0.1m on all sides. The ground plane is connected to the protective earth. The length of power cord between the coupling device and the EUT was less than 2 meters (provided by the manufacturer).
- b. The EUT was connected to the power mains through a coupling device that directly couples the surge interference signal. The surge noise was applied synchronized to the voltage phase at the zero crossing and the peak value of the AC voltage wave (positive and negative).
- c. The surges were applied line to line and line(s) to earth. All lower levels including the selected test level were tested. The polarity of each surge level included positive and negative test pulses.

#### 15.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 38 of 48

#### 15.4. TEST RESULT

Coupling Line	Polarity	Voltage (kV)	Test Mode	Performance criteria	
a.c. power, L-N	+/-	Mode 1	А		
A: No degradation in the performance of the ELIT was observed					

A: No degradation in the performance of the EUT was observed.

#### 15.5. PERFORMANCE

The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.  The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.  Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.  Compliance Not Compliance	101011 =111 011	
or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.  Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	⊠Criteria A:	function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a
restored by the operation of controls.	□Criteria B:	or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however
☐ Compliance ☐ Not Compliance	☐Criteria C:	
☐ Compliance ☐ Not Compliance		
	⊠ Complianc	e 🗌 Not Compliance



Page 39 of 48

#### 16. IMMUNITY TO CONDUCTED DISTURBANCES INDUCED BY RF FIELDS

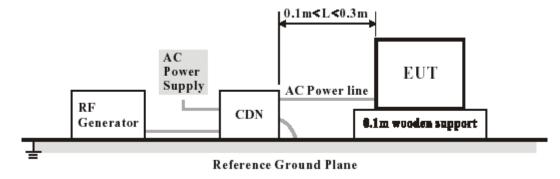
#### 16.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-6
Frequency Range	0.15MHz-80MHz
Field Strength	3Vrms
Modulation	1 kHz Sine Wave, 80% AM
Frequency Step	1% of fundamental
Coupled Cable	a.c. power line
Coupling Device	CDN-M2

#### **16.2. TEST PROCEDURE**

- 1. The EUT shall be tested within its intended operating and climatic conditions.
- The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn, while the other non-excited RF input ports of the coupling devices are terminated by a 50-ohm load resistor.
- 3. The test signal was 80% amplitude modulated with a 1 kHz sine wave
- 4. The frequency range is swept from 150 kHz to 80 MHz, using the signal level established during the setting process and with a disturbance signal of 80% amplitude. The sweep rate shall not exceed 1.5×10-3 decades/s. The step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value where the frequency is swept incrementally.
- 5. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised, and able to respond. Sensitive frequencies such as clock frequencies and harmonics or frequencies of dominant interest, shall be analyzed separately.
- 6. Attempts should be made to fully exercise the EUT during test, and to fully interrogate all exercise modes selected for susceptibility.

#### 16.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 40 of 48

## 16.4. TEST RESULT

Test Point	Frequency (MHz)	Level (V rms)	Test Mode	Performance criteria	
a.c. port	Mode 1	Α			
A: No degradation in the performance of the EUT was observed.					

#### **16.5. PERFORMANCE**

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.	
□Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.	
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.	
⊠ Compliance □ Not Compliance		

Any report having not been signed by authorized approver, or having been altered without authorization, or having not been stamped by the "Dedicated Testing/Inspection
Stamp" is deemed to be invalid. Copying or excerpting portion of, or altering the content of the report is not permitted without the written authorization of AGC. The test results
presented in the report apply only to the tested sample. Any objections to report issued by AGC should be submitted to AGC within 15days after the issuance of the test report.
Further enquiry of validity or verification of the test report should be addressed to AGC by agc01@agccert.com.



Page 41 of 48

#### 17. VOLTAGE DIPS AND SHORT INTERRUPTIONS IMMUNITY TEST

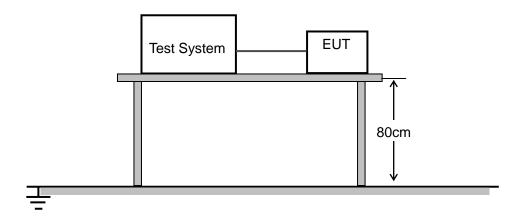
#### 17.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-11		
	100% reduction, 0.5 Cycle		
Voltage Dips	100% reduction, 1.0 Cycle		
	30% reduction, 25 Cycles		
Voltage Interruptions 100% reduction, 250 Cycles			
Voltage Phase Angle 0°, 45°, 90°, 135°, 180°, 225°, 270°, 315°			

#### 17.2. TEST PROCEDURE

- a). The power cord was used as supplied by the manufacturer. The EUT was connected to the line output of the Voltage Dips and Interruption Generator.
- b). The EUT was tested for (1) 100% voltage dip of supplied voltage with duration of 0.5 cycles, (2)100% voltage dip of supplied voltage and duration 1.0 cycle. (3) 30% voltage dip of supplied voltage and duration 25 cycles. (4) 100% voltage interruption of supplied voltage with duration of 250 Cycles was followed.
- c). Voltage reductions occur at 0 degree crossover point of the voltage waveform. The performance of the EUT was checked after the voltage dip or interruption.

#### 17.3. TEST SETUP



For the actual test configuration, please refer to Appendix A, Photographs of the Test Configuration.



Page 42 of 48

#### 17.4. TEST RESULT

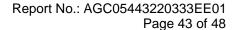
Test Mode	Voltage Reduction	Duration (cycle)	Times	Interval (Sec)	Test Mode	Performance criteria
	100%	0.5	3	10	Mode 1	В
Voltage dips	100%	1	3	10	Mode 1	В
	30%	25	3	10	Mode 1	В
Voltage interruptions	100%	250	3	10	Mode 1	С

- A: No degradation in the performance of the EUT was observed.
- B: Stop charging during the test and self-recoverable after test.
- C: Lost functions can be recoverable by user or operator.

#### 17.5. PERFORMANCE

□Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
⊠Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
⊠Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

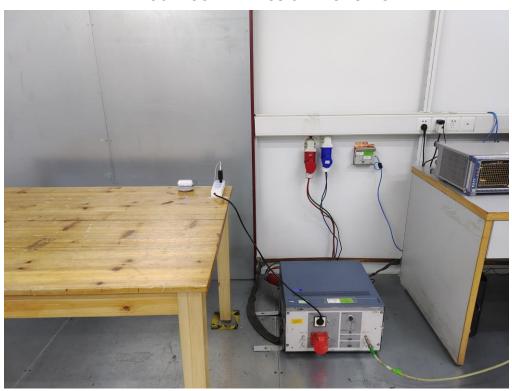
⊠ Compliance [	☐ Not Compliance
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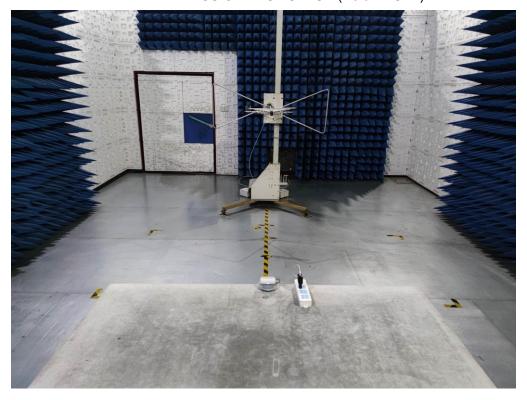


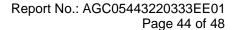
## **APPENDIX A: PHOTOGRAPHS OF TEST SETUP**

LINE CONDUCTED EMISSION TEST SETUP



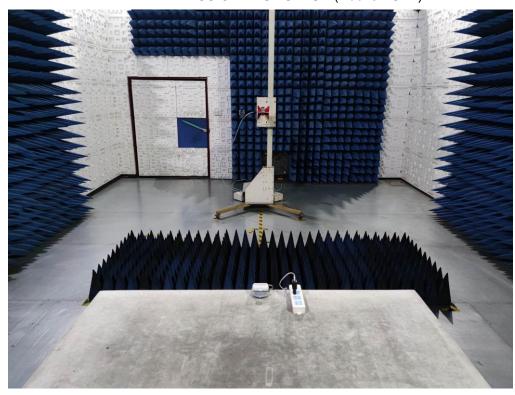
RADIATED EMISSION TEST SETUP (Below 1GHz)





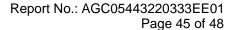


RADIATED EMISSION TEST SETUP (Above 1GHz)



EN61000-3-3 HARMONIC CURRENT/VOLTAGE FLUCTUATION ANDFLICKER TEST SETUP



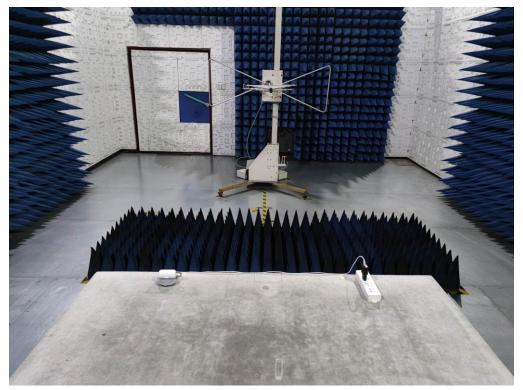


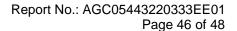


#### EN 61000-4-2 ESD TEST SETUP



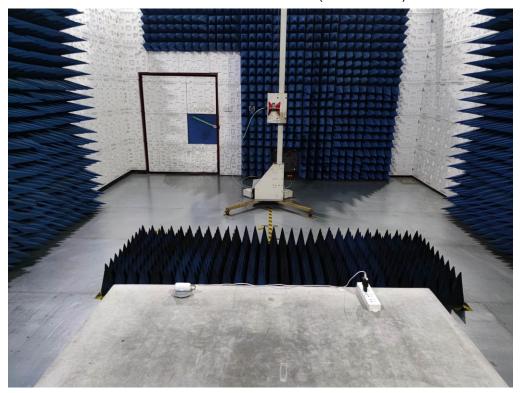
EN 61000-4-3 RS TEST SETUP (Below 1GHz)



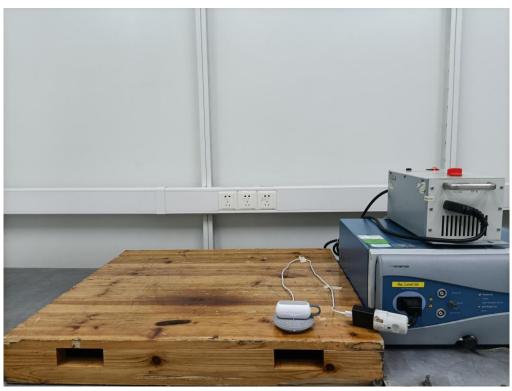




EN 61000-4-3 RS TEST SETUP (Above 1GHz)

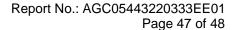


EN 61000-4-4/-5/-11EFT/SURGE/DIPS IMMUNITY TEST SETUP



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Tel: +86-755 2523 4088 E-mail: agc@agccert.com Web: http://www.agccert.com/





#### EN 61000-4-6 CS IMMUNITY TEST SETUP





Page 48 of 48

#### APPENDIX B: PHOTOGRAPHS OF THE EUT

Refer to the Report No.: AGC05443220333AP01

----END OF REPORT----



## Conditions of Issuance of Test Reports

- 1. All samples and goods are accepted by the Attestation of Global Compliance (Shenzhen) Co., Ltd (the "Company") solely for testing and reporting in accordance with the following terms and conditions. The company provides its services on the basis that such terms and conditions constitute express agreement between the company and any person, firm or company requesting its services (the "Clients").
- 2. Any report issued by Company as a result of this application for testing services (the "Report") shall be issued in confidence to the Clients and the Report will be strictly treated as such by the Company. It may not be reproduced either in its entirety or in part and it may not be used for advertising or other unauthorized purposes without the written consent of the Company. The Clients to whom the Report is issued may, however, show or send it, or a certified copy thereof prepared by the Company to its customer, supplier or other persons directly concerned. The Company will not, without the consent of the Clients, enter into any discussion or correspondence with any third party concerning the contents of the Report, unless required by the relevant governmental authorities, laws or court orders.
- 3. The Company shall not be called or be liable to be called to give evidence or testimony on the Report in a court of law without its prior written consent, unless required by the relevant governmental authorities, laws or court orders.
- 4. In the event of the improper use of the report as determined by the Company, the Company reserves the right to withdraw it, and to adopt any other additional remedies which may be appropriate.
- 5. Samples submitted for testing are accepted on the understanding that the Report issued cannot form the basis of, or be the instrument for, any legal action against the Company.
- 6. The Company will not be liable for or accept responsibility for any loss or damage however arising from the use of information contained in any of its Reports or in any communication whatsoever about its said tests or investigations.
- 7.Clients wishing to use the Report in court proceedings or arbitration shall inform the Company to that effect prior to submitting the sample for testing.
- 8. The Company is not responsible for recalling the electronic version of the original report when any revision is made to them. The Client assumes the responsibility to providing the revised version to any interested party who uses them.
- 9. Subject to the variable length of retention time for test data and report stored hereinto as otherwise specifically required by individual accreditation authorities, the Company will only keep the supporting test data and information of the test report for a period of six years. The data and information will be disposed of after the aforementioned retention period has elapsed. Under no circumstances shall we provide any data and information which has been disposed of after retention period. Under no circumstances shall we be liable for damage of any kind, including (but not limited to) compensatory damages, lost profits, lost data, or any form of special, incidental, indirect, consequential or punitive damages of any kind, whether based on breach of contract of warranty, tort (including negligence), product liability or otherwise, even if we are informed in advance of the possibility of such damages.



# **EMC Test Report**

Report No.: AGC05443220333EE02

**PRODUCT DESIGNATION**: Wireless charging earbuds

BRAND NAME : N/A

MODEL NAME : MO9768

**APPLICANT**: MID OCEAN BRANDS B.V

**DATE OF ISSUE** : Apr. 14, 2022

EN 55032: 2015/A11:2020

**STANDARD(S)** EN IEC 61000-3-2:2019

EN 61000-3-3:2013/A1:2019

EN 55035:2017/A11:2020

**REPORT VERSION**: V1.0

Attestation of Global Compliance (Shenzhen) Co., Ltd





Page 2 of 59

#### REPORT REVISE RECORD

Report Version	Revise Time	Issued Date	Valid Version	Notes
V1.0	/	Apr. 14, 2022	Valid	Initial release

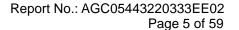


## **TABLE OF CONTENTS**

1. VERIFICATION OF CONFORMITY	5
2. SYSTEM DESCRIPTION	6
3. MEASUREMENT UNCERTAINTY	6
4. PRODUCT INFORMATION	7
5. SUPPORT EQUIPMENT	8
6. IDENTIFICATION OF THE RESPONSIBLE TESTING LOCATION	9
7. EN 55032 LINE CONDUCTED EMISSION TEST	11
7.1. LIMITS OF LINE CONDUCTED EMISSION TEST	11 12
8. EN 55032 RADIATED EMISSION TEST	
8.1. LIMITS OF RADIATED DISTURBANCES	16
9. POWER HARMONICS TEST	22
9.1. BLOCK DIAGRAM OF TEST SETUP	
10. VOLTAGE FLUCTUATION / FLICKER TEST	23
10.1. BLOCK DIAGRAM OF TEST SETUP	
11. ESD IMMUNITY TEST	25
11.1. BLOCK DIAGRAM OF TEST SETUP	26
12. RADIATED, RADIO FREQUENCY ELECTROMAGNETIC FIELD IMMUNITY TEST	29
12.1. TEST SPECIFICATION	29



12.2. TEST PROCEDURE	29
12.3. TEST SETUP	30
12.4. TEST RESULT	31
12.5. PERFORMANCE	31
13. ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST	32
13.1. TEST SPECIFICATION	32
13.2. TEST PROCEDURE	32
13.3. TEST SETUP	32
13.4. TEST RESULT	33
13.5. PERFORMANCE	33
14. SURGE IMMUNITY TEST	34
14.1. TEST SPECIFICATION	34
14.2. TEST PROCEDURE	34
14.3. TEST SETUP	34
14.4. TEST RESULT	35
14.5. PERFORMANCE	35
15. IMMUNITY TO CONDUCTED DISTURBANCES INDUCED BY RF FIELDS	36
15.1. TEST SPECIFICATION	36
15.2. TEST PROCEDURE	36
15.3. TEST SETUP	36
15.4. TEST RESULT	37
15.5. PERFORMANCE	37
16. VOLTAGE DIPS AND SHORT INTERRUPTIONS IMMUNITY TEST	38
16.1. TEST SPECIFICATION	38
16.2. TEST PROCEDURE	38
16.3. TEST SETUP	38
16.4. TEST RESULT	39
16.5. PERFORMANCE	39
APPENDIX A: PHOTOGRAPHS OF TEST SETUP	40
APPENDIX B: PHOTOGRAPHS OF EUT	45





#### 1. VERIFICATION OF CONFORMITY

Applicant	MID OCEAN BRANDS B.V		
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong		
Manufacturer	MID OCEAN BRANDS B.V		
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong		
Factory	MID OCEAN BRANDS B.V		
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong		
Product Designation	Wireless charging earbuds		
Brand Name	N/A		
Test Model	MO9768		
Date of test	Mar. 31, 2022 to Apr. 12, 2022		
Deviation	None		
Condition of Test Sample	Normal		
Report Template	AGCRT-EC-IT/AC(2013-03-01)		

The above equipment was tested by Attestation of Global Compliance (Shenzhen) Co., Ltd. for compliance with the requirements of Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment.

The test results of this report relate only to the tested sample identified in this report.

Prepared By

John Zeng
(Project Engineer)

Reviewed By

Calvin Liu
(Reviewer)

Apr. 14, 2022

Apr. 14, 2022

Apr. 14, 2022

Apr. 14, 2022



Page 6 of 59

#### 2. SYSTEM DESCRIPTION

TEST MODE DESCRIPTION						
NO. EMI TEST MODE DESCRIPTION WORST						
1 USB Charging mode with adapter V						
NO. EMS TEST MODE DESCRIPTION WORST						
1	USB Charging mode with adapter	V				
Note: 1. V means EMI worst mode.						

#### 3. MEASUREMENT UNCERTAINTY

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in measurement" (GUM) published by ISO.

- Uncertainty of Conducted Emission, Uc = ±2.9 dB
- Uncertainty of Radiated Emission below 1GHz, Uc = ±3.8 dB
- Uncertainty of Radiated Emission above 1GHz, Uc = ±4.9 dB



Page 7 of 59

#### 4. PRODUCT INFORMATION

Housing Type	Plastic
Hardware Version	Bluetooth-AF0031 V1.0
Software Version	leader.1910.01 V5.0
Power Supply(Headset)	DC 3.7V by battery
Power Supply(Charging Dock)	DC 3.7V by battery or DC 5V by adapter

## I/O Port Information (⊠Applicable ☐Not Applicable)

I/O Port of EUT				
I/O Port Type	Tested With			
Type-C Port(for charging dock)	1	0.3m unshielded	1	
Charging Port (for headset)	2		2	

Note: All the above "—" means that EUT has no cab.



## 5. SUPPORT EQUIPMENT

Device Type	Manufacturer	Model	Serial No	Data Cable	Mains cable
Adapter	jinbaotong	K-T10E0502000E			DC 5V



Page 9 of 59

## 6. IDENTIFICATION OF THE RESPONSIBLE TESTING LOCATION

Site	Attestation of Global Compliance (Shenzhen) Co., Ltd
Location	1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao'an District, Shenzhen, Guangdong, China

#### TEST EQUIPMENT OF CONDUCTED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESPI	101206	Mar.28, 2022	Mar.27, 2023
Artificial power network	R&S	ESH2-Z5	100086	Jun. 09, 2021	Jun. 08, 2022
Test Software	FARA	EZ-EMC(Ver. AGC-CON03A1)	N/A	N/A	N/A

#### **TEST EQUIPMENT OF RADIATED EMISSION TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESCI	100034	Sep. 06, 2021	Sep. 05, 2022
Wideband Antenna	SCHWARZBE CK	VULB9168	D69250	Apr. 28, 2021	Apr. 27, 2023
Double-Ridged Waveguide Horn	ETS	3117	00154520	Sep. 06, 2021	Sep. 05, 2023
Preamplifier Assembly	ETS	3117PA	00225134	Sep. 03, 2020	Sep. 02, 2022
EXA Signal Analyzer	Aglient	N9010A	MY53470504	Nov. 17, 2021	Nov. 16, 2022
Test software	FARA	EZ-EMC (Ver.RA-03A)	N/A	N/A	N/A
Test Software	Tonscend	JS32-RE(Ver.2.5)	N/A	N/A	N/A

#### TEST EQUIPMENT OF POWER HARMONICS / VOLTAGE FLUCTUATION / FLICKER TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Conditioning Unit	Schaffner	CCN1000-1	72431	Jul. 19, 2021	Jul. 18, 2022
AC Source	Schaffner	NSG1007	56825	Jul. 19, 2021	Jul. 18, 2022

#### **TEST EQUIPMENT OF ESD TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
ESD Simulator	Schaffner	NSG 438	782	Jan. 03, 2022	Jan. 02, 2023



Page 10 of 59

#### **TEST EQUIPMENT OF RS IMMUNITY TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Generator	KEYSIGHT	N5182A	N5182A	Mar. 04, 2022	Mar.03, 2023
Power Probe	R&S	URV5-Z4	100124	Apr. 26, 2021	Apr. 25, 2023
Power Meter	R&S	NRVD	8323781027	Apr. 26, 2021	Apr. 25, 2023
Power Amplifier	Power Amplifier L2		BPA00T10W 500-1	N/A	N/A
Power Amplifier	Milmega	AS0104-55_55	1004793	N/A	N/A
Power Amplifier	Power Amplifier Rflight		17063183	N/A	N/A
Broadband High Gain Horn Antenna			00073	N/A	N/A
Double-Ridged Waveguide Horn			00034609	Apr. 23, 2021	Apr. 22, 2023
Wideband Antenna	SCHWARZBECK	VULB9168	D69250	Apr. 28, 2021	Apr. 27, 2023

#### **TEST EQUIPMENT OF SURGE/EFT/DIPS TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
EFT/Surge/DIPS Generator	Schaffner	Modula 6150	34437	Jul. 19, 2021	Jul. 18, 2022

#### **TEST EQUIPMENT OF CS IMMUNITY TEST**

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Power Amplifier	AR	75A250	18464	N/A	N/A
CDN	ZHINAN	ZN3751	15004	Sep. 03, 2020	Sep. 02, 2022
6dB attenuator	dB attenuator ZHINAN		N/A	Sep. 03, 2020	Sep. 02, 2022
Power Probe	R&S	URV5-Z4	100124	Apr. 26, 2021	Apr. 25, 2023
Electromagnetic Injection Clamp	Luthi EM101		35773	Aug. 25, 2020	Aug. 24, 2022
Power Meter	Meter R&S NRVD		8323781027	Apr. 26, 2021	Apr. 25, 2023
Signal Generator	Aglient	E4421B	MY43351603	Mar. 04, 2022	Mar.03, 2023



Page 11 of 59

#### 7. EN 55032 LINE CONDUCTED EMISSION TEST

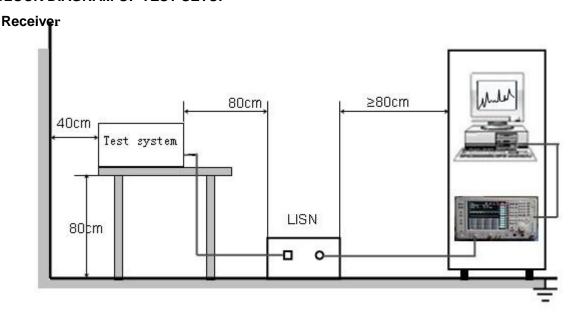
#### 7.1. LIMITS OF LINE CONDUCTED EMISSION TEST

Fraguency	Maximum RF Line Voltage				
Frequency	Q.P.(dBuV)	Average(dBuV)			
150kHz-500kHz	66-56	56-46			
500kHz-5MHz	56	46			
5MHz-30MHz	60	50			

Note: 1. The lower limit shall apply at the transition frequency.

2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50MHz.

#### 7.2. BLOCK DIAGRAM OF TEST SETUP





Page 12 of 59

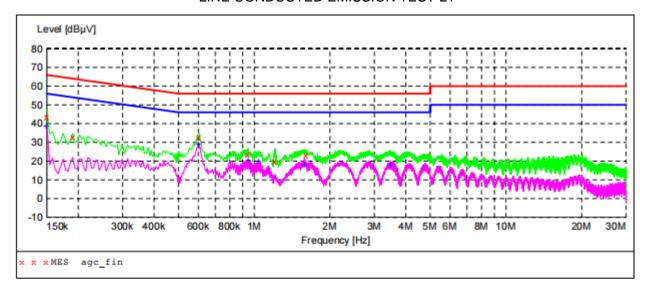
#### 7.3. PROCEDURE OF LINE CONDUCTED EMISSION TEST

- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN55032 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN55032.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN55032.
- (4) The EUT received charging voltage by adapter through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.
- (5) All support equipments received power from a second LISN supplying power of AC 230V/50Hz, if any.
- (6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- (7) Analyzer / Receiver scanned from 150 kHz to 30 MHz for emissions in each of the test modes.
- (8) During the above scans, the emissions were maximized by cable manipulation.
- (9) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions.
- (10) Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.



#### 7.4. TEST RESULT OF LINE CONDUCTED EMISSION TEST

#### LINE CONDUCTED EMISSION TEST-L1



#### MEASUREMENT RESULT: "agc fin"

2022/4/2 2 Frequenc	y Level	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.15000		6.9	66	22.6	QP	L1	GND
0.19000		6.6	64	31.4	QP	L1	GND
0.60200		5.4	56	23.5	QP	L1	GND
0.94600		5.4	56	32.4	QP	L1	GND
1.21000		5.7	56	35.9	QP	L1	GND
1.60200	0 23.20	6.1	56	32.8	QP	L1	GND

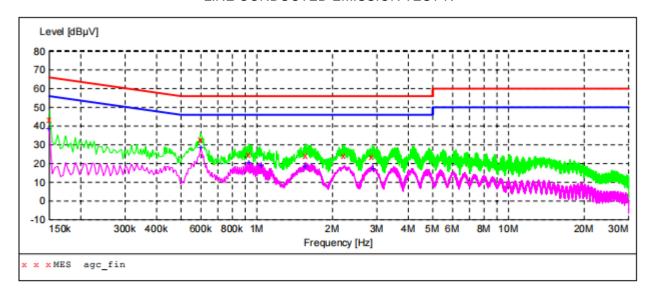
## MEASUREMENT RESULT: "agc\_fin2"

2022/4/2 22: Frequency MHz	28 Level dBμV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000	38.50	6.9	56	17.5	AV	L1	GND
0.602000	29.20	5.4	46	16.8	AV	L1	GND
0.946000	20.40	5.4	46	25.6	AV	L1	GND
1.042000	19.80	5.5	46	26.2	AV	L1	GND
1.586000	17.80	6.1	46	28.2	AV	L1	GND
3.486000	17.70	6.5	46	28.3	AV	L1	GND

**RESULT: PASS** 



#### LINE CONDUCTED EMISSION TEST-N



## MEASUREMENT RESULT: "agc\_fin"

2022/4/2 22:30 Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000	43.50	6.9	66	22.5	QP	N	GND
0.598000	33.00	5.4	56	23.0	QP	N	GND
0.930000	24.90	5.4	56	31.1	QP	N	GND
1.562000	24.30	6.1	56	31.7	QP	N	GND
2.214000	24.00	6.5	56	32.0	QP	N	GND
2.874000	23.60	6.5	56	32.4	QP	N	GND

#### MEASUREMENT RESULT: "agc fin2"

2022/4/2 22:30 Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.150000 0.598000 0.930000 1.042000 1.562000 2.890000	38.60 28.50 20.40 19.00 18.40 17.50	6.9 5.4 5.4 5.5 6.1 6.5	56 46 46 46 46	17.4 17.5 25.6 27.0 27.6 28.5	AV AV AV AV AV	N N N N	GND GND GND GND GND GND

**RESULT: PASS** 



Page 15 of 59

#### 8. EN 55032 RADIATED EMISSION TEST

#### **8.1. LIMITS OF RADIATED DISTURBANCES**

#### **AT 3M DISTANCES**

## For class B equipment

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m Q.P.)
30-230	3	40
230-1000	3	47

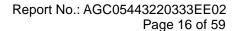
#### For class B equipment

Erogueney rango (MUT)	Limits (dBuV/m), Class B ITE				
Frequency range (MHz)	Peak	Average			
1000-3000	70	50			
3000-6000	74	54			

#### For FM receivers

Frequency	Distance		ield Strength Limit uV/m Q.P.)
(MHz)	(m)	Fundamental	Harmonics
30-230	3		52
230-300	3	60	52
300-1000	3		56

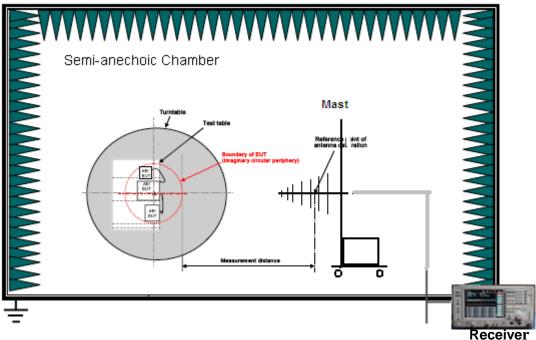
**Note:** The lower limit shall apply at the transition frequency.



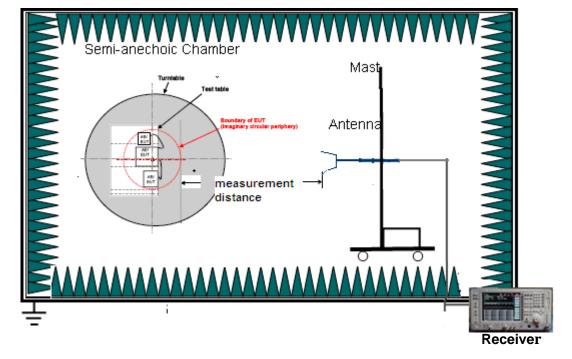


#### **8.2. BLOCK DIAGRAM OF TEST SETUP**

#### Radiated Disturbance below 1 GHz



Radiated Disturbance above 1 GHz





Page 17 of 59

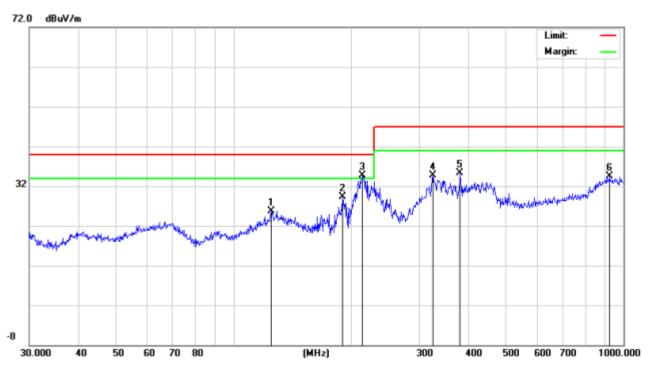
#### 8.3. PROCEDURE OF RADIATED EMISSION TEST

- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55032 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN 55032.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN 55032.
- (4) The EUT received charging voltage by Adapter which got power through the outlet socket under the turntable. All support equipment received AC 230V/50Hz power from socket under the turntable, if any.
- (5) The antenna was placed at 3 meters away from the EUT as stated in EN 55032. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- (6) For the test below 1GHz, the Analyzer / Receiver quickly scanned from 30MHz to 1000MHz using 100 kHz RBW and 300 kHz VBW. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and the antenna height scan shall be restricted to a range of 1 m to 4 m above the RGP, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- (7) For the test above 1GHz, the Analyzer / Receiver quickly scanned from 1 GHz to the highest measured frequency using 1 MHz RBW and 3 MHz VBW. The highest measured frequency is defined in Table 1 of CISPR 32. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and the antenna height scan shall encompass those heights defined in Figure 14, Figure 15 and Table 2 of CISPR 16-2-3:2010 AMD1:2010, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- (8) The test mode(s) were scanned during the test:
- (9) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. For testing below 1GHz, the emissions level of the EUT in peak mode was lower than Q.P. limit (that means the emissions level in Q.P. mode also complies with the limit in Q.P. mode), then testing will be stopped and peak values of EUT will be reported, otherwise, the emissions will be measured in Q.P. mode again and reported. For testing above 1GHz, the emissions level of the EUT in peak mode was lower than average limit (that means the emissions level in average mode also complies with the limit in average mode), then testing will be stopped and peak values of EUT will be reported, otherwise, the emissions will be measured in average mode again and reported.



#### 8.4. TEST RESULT OF RADIATED EMISSION TEST

#### RADIATED EMISSION BELOW 1GHZ-HORIZONTAL

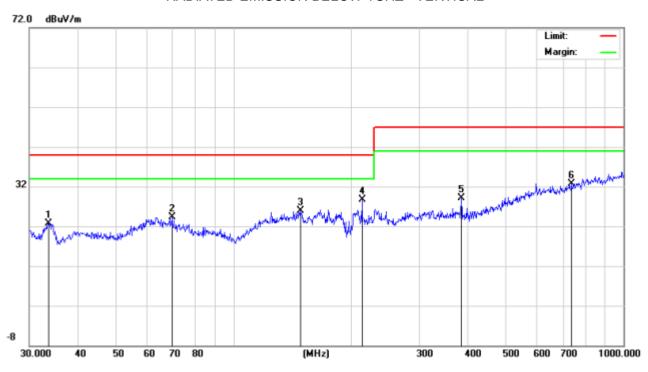


No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector
1		125.0066	6.90	18.89	25.79	40.00	-14.21	peak
2		190.4050	14.27	15.04	29.31	40.00	-10.69	peak
3	*	214.5143	17.33	17.37	34.70	40.00	-5.30	peak
4	,	324.4561	10.53	24.25	34.78	47.00	-12.22	peak
5		381.2487	11.44	23.82	35.26	47.00	-11.74	peak
6	(	922.5157	5.58	28.89	34.47	47.00	-12.53	peak

**RESULT: PASS** 



#### RADIATED EMISSION BELOW 1GHZ- VERTICAL

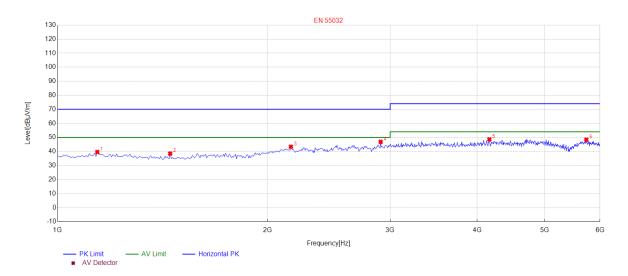


No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector
1		33.5623	9.52	13.28	22.80	40.00	-17.20	peak
2		69.6004	6.18	18.10	24.28	40.00	-15.72	peak
3		148.4410	7.47	18.37	25.84	40.00	-14.16	peak
4	*	213.7633	13.14	15.56	28.70	40.00	-11.30	peak
5		383.9318	8.98	20.06	29.04	47.00	-17.96	peak
6		737.0714	5.67	26.99	32.66	47.00	-14.34	peak

**RESULT: PASS** 



#### RADIATED EMISSION ABOVE 1GHz - HORIZONTAL

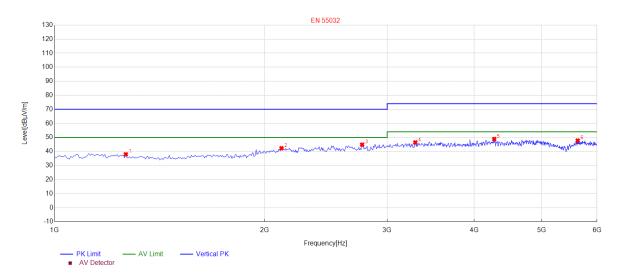


NO.	Freq. [MHz]	Level [dBµV/m]	Factor [dB]	Limit [dBµV/m]	Margin [dB]	Height [cm]	Angle []	Polarity
1	1140.1401	39.61	-16.78	70.00	30.39	100	180	Horizontal
2	1450.4504	38.55	-17.08	70.00	31.45	100	270	Horizontal
3	2161.1612	43.37	-11.14	70.00	26.63	100	280	Horizontal
4	2906.9069	46.88	-9.40	70.00	23.12	100	260	Horizontal
5	4163.1632	48.61	-6.08	74.00	25.39	100	90	Horizontal
6	5734.7347	48.38	-4.54	74.00	25.62	100	340	Horizontal

**RESULT: PASS** 



## RADIATED EMISSION ABOVE 1GHz - VERTICAL



NO.	Freq.	Level	Factor	Limit	Margin	Height	Angle	Polarity
	[MHz]	[dBµV/m]	[dB]	[dBµV/m]	[dB]	[cm]	[ግ	Fulality
1	1265.2653	37.96	-16.90	70.00	32.04	100	350	Vertical
2	2116.1161	42.30	-11.33	70.00	27.70	100	290	Vertical
3	2761.7618	44.87	-9.52	70.00	25.13	100	90	Vertical
4	3292.2923	46.40	-8.32	74.00	27.60	100	330	Vertical
5	4273.2733	48.82	-5.79	74.00	25.18	100	170	Vertical
6	5629.6296	47.76	-4.88	74.00	26.24	100	190	Vertical

**RESULT: PASS** 

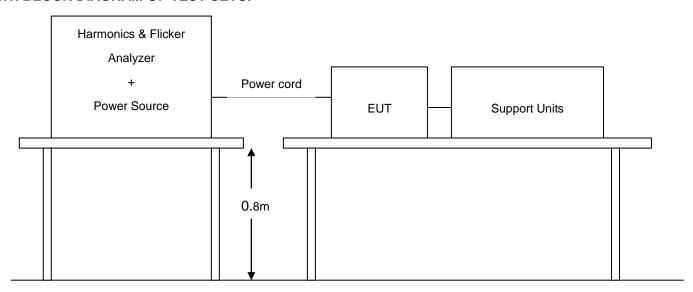


Page 22 of 59

#### 9. POWER HARMONICS TEST

Port	AC mains
Basic Standard	EN IEC 61000-3-2
Limits	⊠CLASS A; □CLASS B; □CLASS C; □CLASS D
Temperature	25°C
Relative Humidity	55%

#### 9.1. BLOCK DIAGRAM OF TEST SETUP



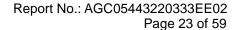
#### 9.2. RESULT

#### **Test Specification**

Test Frequency	50Hz	Test Voltage	230V AC
Waveform	Sine	Test Time	2.5min
Classification	Class A		

Note: 1.The active input power of the EUT is less than 75W.

2. No limits apply for equipment with an active input power up to and including 75W.

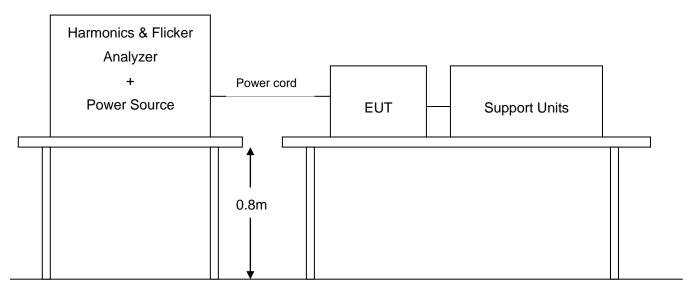


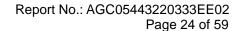


## 10. VOLTAGE FLUCTUATION / FLICKER TEST VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

Port	AC mains
Basic Standard	EN 61000-3-3
Limits	§5 of EN 61000-3-3
Temperature	23°C
Relative Humidity	53%

#### 10.1. BLOCK DIAGRAM OF TEST SETUP





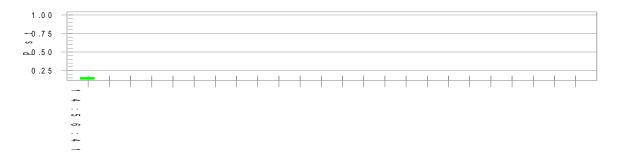


# **10.2. RESULT**

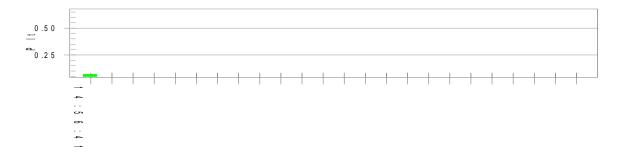
# Flicker Test Summary per EN/IEC61000-3-3 (Run time)

Test Result: Pass Status: Test Completed

# Psti and limit line European Limits

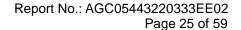


# Plt and limit line



# Parameter values recorded during the test:

Vrms at the end of test (Volt):	230.58			
Highest dt (%):	0.00	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.30	Pass
Highest dmax (%):	0.00	Test limit (%):	4.00	Pass
Highest Pst (10 min. period):	0.160	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.070	Test limit:	0.650	Pass





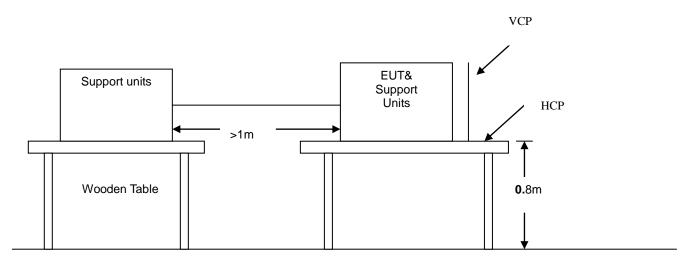
# 11. ESD IMMUNITY TEST

# **ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST**

Port	Enclosure
Basic Standard	EN 61000-4-2
Test Level	± 8.0 kV (Air Discharge) ± 4.0 kV (Contact Discharge) ± 4.0 kV (Indirect Discharge)
Standard require	В
Temperature	24.2°C
Relative Humidity	54%

# 11.1. BLOCK DIAGRAM OF TEST SETUP

(The 470 k ohm resistors are installed per standard requirement)



Ground Reference Plane

For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 26 of 59

#### 11.2. TEST PROCEDURE

The EUT was located 0.1 m minimum from all side of the HCP.

The support units were located 1 m minimum away from the EUT.

EUT worked with resistance load, and make sure EUT worked normally.

Actives the communication function if the EUT with such port(s).

As per the requirement of EN 55035: Contact discharge is the preferred test method. 20 discharges (10 with positive and 10 negative polarity) shall be applied on each accessible metal part of the enclosure. In case of a non-conductive enclosure, discharges shall be applied on the horizontal or vertical coupling planes as specified in EN 61000-4-2.

Air discharges shall be used where contact discharges cannot be applied.

The following test condition was followed during the tests.

Note: As per the A2 to EN 61000-4-2, a bleed resistor cable is connected between the EUT and HCP during the test.

The electrostatic discharges were applied as follows:

#### 11.3. PERFORMANCE & RESULT

Amount of Discharges	Voltage	Coupling	Performance	Conclusion
Mini 20 /Point	±4kV	Contact Discharge	А	PASS
Mini 20 /Point	±4kV	Indirect Discharge HCP (Front)	Α	PASS
Mini 20 /Point	±4kV	Indirect Discharge HCP (Left)	Α	PASS
Mini 20 /Point	±4kV	Indirect Discharge HCP (Back)	А	PASS
Mini 20 /Point	±4kV	Indirect Discharge HCP (Right)	Α	PASS
Mini 20 /Point	±4kV	Indirect Discharge VCP (Front)	А	PASS
Mini 20 /Point	±4kV	Indirect Discharge VCP (Left)	А	PASS
Mini 20 /Point	±4kV	Indirect Discharge VCP (Back)	А	PASS
Mini 20 /Point	±4kV	Indirect Discharge VCP (Right)	А	PASS
Mini 20 /Point	±8kV	Air Discharge	А	PASS

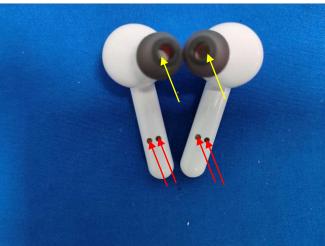


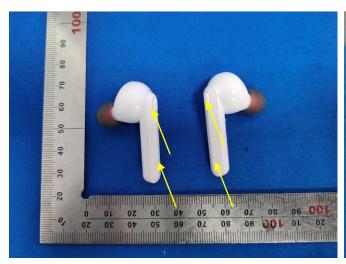
Page 27 of 59

# **ESD LOCATION:**

Yellow line: Air discharge Red line: Contact discharge











Page 28 of 59

# 11.4. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

<b>⊠</b> PASS	□FAIL



Page 29 of 59

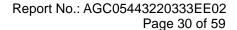
# 12. RADIATED, RADIO FREQUENCY ELECTROMAGNETIC FIELD IMMUNITY TEST 12.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-3
Frequency Range	80-1000, 1800, 2600, 3500, 5000(MHz)
Field Strength	3V/m
Modulation	1 kHz sine wave, 80%, AM modulation
Frequency Step	1% of fundamental
Polarity of Antenna	Horizontal and Vertical
Test Distance	3m
Antenna Height	1.5m
Dwell Time	3 seconds

# **12.2. TEST PROCEDURE**

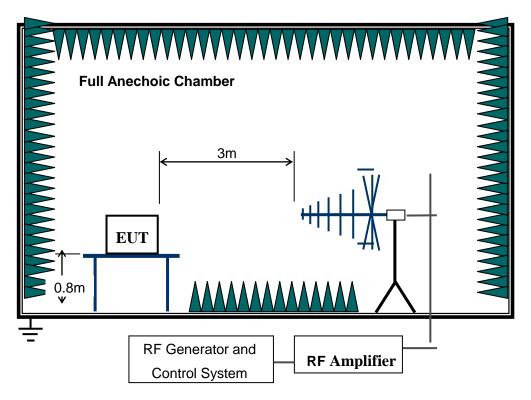
The test procedure was in accordance with EN 61000-4-3.

- a. The testing was performed in a fully anechoic chamber. The transmit antenna was located at a distance of 3 meters from the EUT.
- b. The test signal was 80% amplitude modulated with a 1 kHz sine wave.
- c. The frequency range was swept at 80-1000, 1800, 2600, 3500, 5000(MHz) with the exception of the exclusion band for transmitters, receivers and duplex transceivers. The rate of sweep did not exceed 1.5×10<sup>-3</sup> decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- d. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- e. The field strength level was 3V/m.
- f. The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.





# 12.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 31 of 59

# 12.4. TEST RESULT

Freq. Range (MHz)	Field	Modulation	Polarity	Position	Observation	performance	Conclusion
80-1000,1800,2 600,3500,5000	3V/m	Yes	H/V	Front	No Function Loss	А	PASS
80-1000,1800,2 600,3500,5000	3V/m	Yes	H/V	Back	No Function Loss	А	PASS
80-1000,1800,2 600,3500,5000	3V/m	Yes	H/V	Left	No Function Loss	А	PASS
80-1000,1800,2 600,3500,5000	3V/m	Yes	H/V	Right	No Function Loss	А	PASS
80-1000,1800,2 600,3500,5000	3V/m	Yes	H/V	Тор	No Function Loss	А	PASS
80-1000,1800,2 600,3500,5000	3V/m	Yes	H/V	Bottom	No Function Loss	А	PASS

Note: operating mode include all modes of EMS in page 6.

# 12.5. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.  The measured acoustic interference ratio during the test are less than -20 dB.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
	$\square$ PACC $\square$ FAII

⊠PASS □FAIL
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# 13. ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST

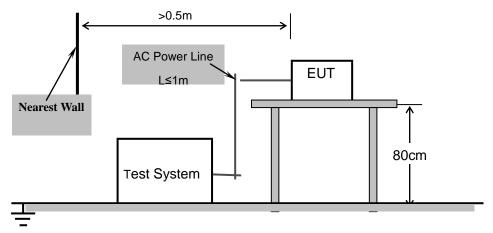
#### 13.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-4
Test Voltage	a.c. power port ± 1kV
Polarity	Positive/Negative
Impulse Frequency	5kHz
Impulse wave shape	5/50ns
<b>Burst Duration</b>	15ms
Burst Period	300ms
Test Duration	Not less than 1 min.

### 13.2. TEST PROCEDURE

- 1. The EUT was tested with 1000 volt discharges to the AC power input leads.
- 2. Both positive and negative polarity discharges were applied.
- 3. The length of the "hot wire" from the coaxial output of the EFT generator to the terminals on the EUT should not exceed 1 meter.
- 4. The duration time of each test sequential was 1 minute.
- 5. The transient/burst waveform was in accordance with EN 61000-4-4, 5/50ns.

#### 13.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 33 of 59

# 13.4. TEST RESULT

Test Point	Polarity	Test Level (kV)	Observation	performance	Conclusion
a.c. port, L	+/-	1	No function loss	А	Pass
a.c. port, N	+/-	1	No function loss	Α	Pass
a.c. port, L-N	+/-	1	No function loss	Α	Pass

Note: operating mode include all modes of EMS in page 6.

# 13.5. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠ <i>PASS</i>	□FAIL



# 14. SURGE IMMUNITY TEST

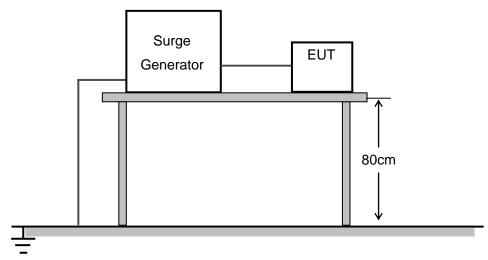
# 14.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-5		
Waveform	Voltage 1.2/50 μs; Current 8/20 μs		
Test Voltage	a.c. power port, line to line ±1.0 kV		
Polarity	Positive/Negative		
Phase Angle	90°, 270°		
Repetition Rate 60sec			
Times	5 time/each condition.		

#### 14.2. TEST PROCEDURE

- a. The EUT and the auxiliary equipment were placed on a table of 0.8m heights above a metal ground reference plane. The size of ground plane is greater than 1m×1m and project beyond the EUT by at least 0.1m on all sides. The ground plane is connected to the protective earth. The length of power cord between the coupling device and the EUT was less than 2 meters (provided by the manufacturer).
- b. The EUT was connected to the power mains through a coupling device that directly couples the surge interference signal. The surge noise was applied synchronized to the voltage phase at the zero crossing and the peak value of the AC voltage wave (positive and negative).
- c. The surges were applied line to line and line(s) to earth. When testing line to earth the test voltage was applied successively between each of the lines and earth. Steps up to the test level specified increased the test voltage. All lower levels including the selected test level were tested. The polarity of each surge level included positive and negative test pulses.

# 14.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 35 of 59

# 14.4. TEST RESULT

Coupling Line	Polarity	Voltage (kV)	Observation	performance	Conclusion
a.c. power, L-N	+/-	1.0	No function loss	Α	Pass

Note: operating mode include all modes of EMS in page 6.

## 14.5. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.



# 15. IMMUNITY TO CONDUCTED DISTURBANCES INDUCED BY RF FIELDS

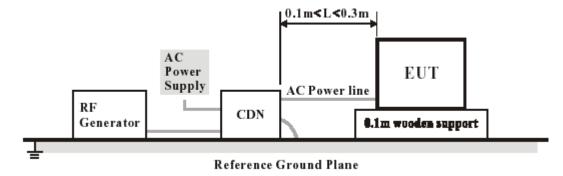
# 15.1. TEST SPECIFICATION

Basic Standard	EN 61000-4-6		
Frequency Range	0.15 MHz – 80 MHz		
Field Strength	0.15~10MHz 3Vrms,10~30MHz 3 to 1Vrms,30~80MHz 1Vrms		
Modulation	1 kHz Sine Wave, 80% AM		
Frequency Step	1% of fundamental		
Coupled Cable	a.c. power line		
Coupling Device	CDN-M2		

#### 15.2. TEST PROCEDURE

- 1. The EUT shall be tested within its intended operating and climatic conditions.
- 2. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn, while the other non-excited RF input ports of the coupling devices are terminated by a 50-ohm load resistor.
- 3. The test signal was 80% amplitude modulated with a 1 kHz sine wave
- 4. The frequency range is swept from 150 kHz to 80 MHz, using the signal level established during the setting process and with a disturbance signal of 80% amplitude. The sweep rate shall not exceed 1.5×10-3 decades/s. The step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value where the frequency is swept incrementally.
- 5. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised, and able to respond. Sensitive frequencies such as clock frequencies and harmonics or frequencies of dominant interest, shall be analyzed separately.
- 6. Attempts should be made to fully exercise the EUT during test, and to fully interrogate all exercise modes selected for susceptibility.

#### 15.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 37 of 59

# 15.4. TEST RESULT

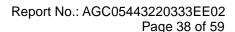
EUT Working Mode	Test Point	Frequency (MHz)	Field Strength (Vrms)	Observation	performance	Conclusion
Normal	a.c. port	0.15 – 10	3	No function loss	А	Pass
Normal	a.c. port	10 – 30	3 to1	No function loss	А	Pass
Normal	a.c. port	30 – 80	1	No function loss	А	Pass

Note: operating mode include all modes of EMS in page 6.

#### 15.5. PERFORMANCE

⊠Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.  The measured acoustic interference ratio during the test are less than -20 dB.
☐Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
☐Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

<b>⊠</b> PASS	☐ FAIL	





16. VOLTAGE DIPS AND SHORT INTERRUPTIONS IMMUNITY TEST

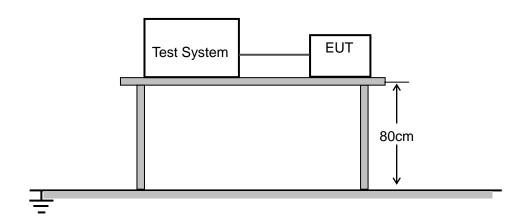
# **16.1. TEST SPECIFICATION**

Basic Standard EN 61000-4-11	
Voltage Dine	100% reduction, 0.5 Cycle
Voltage Dips	30% reduction, 25 Cycles
Voltage Interruptions 100% reduction, 250 Cycles	
Voltage Phase Angle 0°, 45°, 90°, 135°, 180°, 225°, 270°, 315°	

#### **16.2. TEST PROCEDURE**

- a). The power cord was used as supplied by the manufacturer. The EUT was connected to the line output of the Voltage Dips and Interruption Generator.
- b). The EUT was tested for (1) 100% voltage dip of supplied voltage with duration of 0.5 cycles, (2) 30% voltage dip of supplied voltage and duration 25 cycles. (3) 100% voltage interruption of supplied voltage with duration of 250 Cycles was followed.
- c). Voltage reductions occur at 0 degree crossover point of the voltage waveform. The performance of the EUT was checked after the voltage dip or interruption.

#### 16.3. TEST SETUP



For the actual test configuration, please refer to Appendix A: Photographs of the Test Configuration.



Page 39 of 59

# 16.4. TEST RESULT

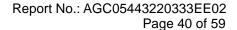
Test Mode	Voltage Reduction	Duration (cycle)	Times	Interval (ms)	Observation	performance	Conclusion
Valtage dine	100%	0.5	3	10	No function loss	В	Pass
Voltage dips	30%	25	3	500	No function loss	В	Pass
Voltage interruptions	100%	250	3	5000	No function loss	С	Pass

Note: operating mode include all modes of EMS in page 6.

# **16.5. PERFORMANCE**

□Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
⊠Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
⊠Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

<b>⊠</b> PASS	□FAIL
<del></del>	_



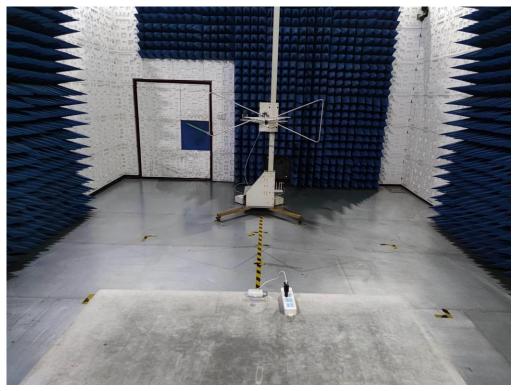


# **APPENDIX A: PHOTOGRAPHS OF TEST SETUP**

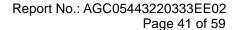
LINE CONDUCTED EMISSION TEST SETUP



RADIATED EMISSION TEST SETUP (Below 1GHz)

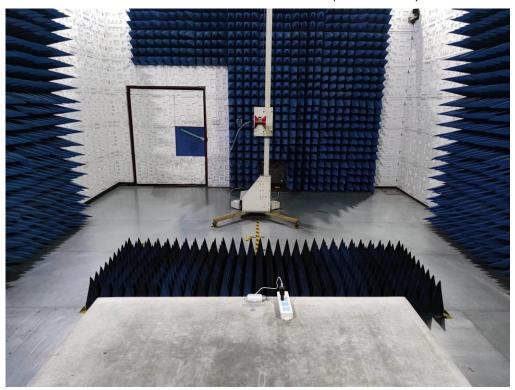


Any report having not been signed by authorized approver, or having been altered without authorization, or having not been stamped by the "Dedicated Testing/Inspection Stamp" is deemed to be invalid. Copying or excerpting portion of, or altering the content of the report is not permitted without the written authorization of AGC. The test results presented in the report apply only to the tested sample. Any objections to report issued by AGC should be submitted to AGC within 15days after the issuance of the test report. Further enquiry of validity or verification of the test report should be addressed to AGC by agc01@agccert.com.



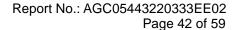






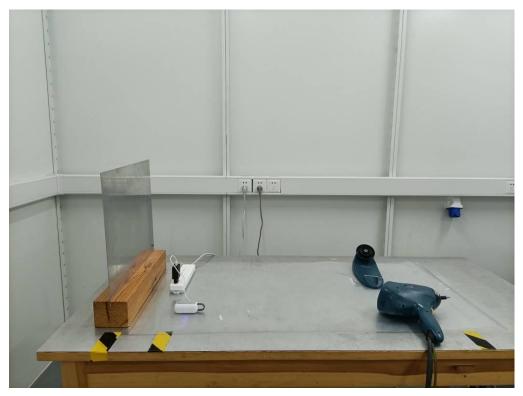
EN61000-3-3 HARMONIC CURRENT/VOLTAGE FLUCTUATION ANDFLICKER TEST SETUP



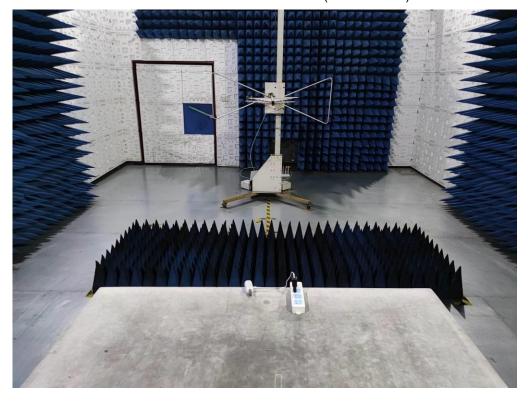




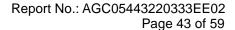
# EN 61000-4-2 ESD TEST SETUP



EN 61000-4-3 RS TEST SETUP (Below 1GHz)

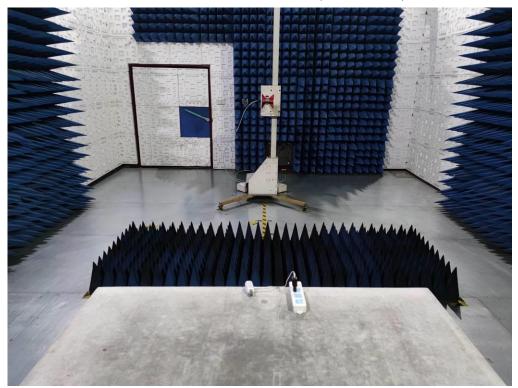


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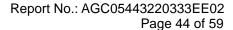






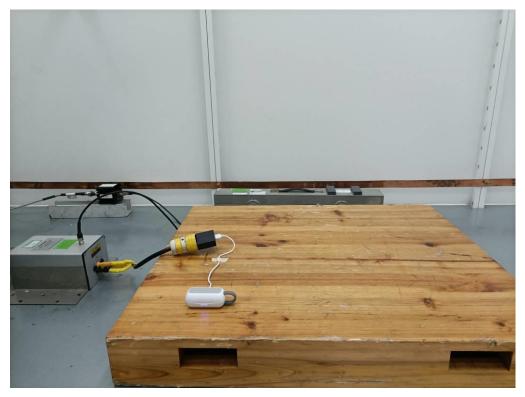
EN 61000-4-4/5/11 EFT/SURGE/DIPS IMMUNITY TEST SETUP

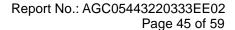














# **APPENDIX B: PHOTOGRAPHS OF EUT**

ALL VIEW OF EUT

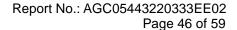


TOP VIEW OF EUT



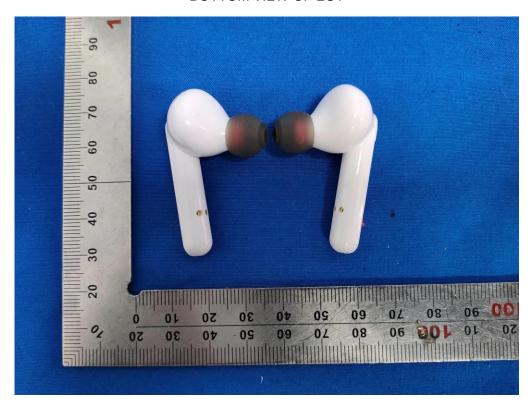
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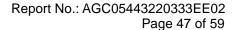
# **BOTTOM VIEW OF EUT**



FRONT VIEW OF EUT



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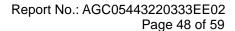
# **BACK VIEW OF EUT**



**LEFT VIEW OF EUT** 



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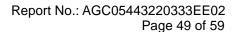
# RIGHT VIEW OF EUT



PORT VIEW OF EUT

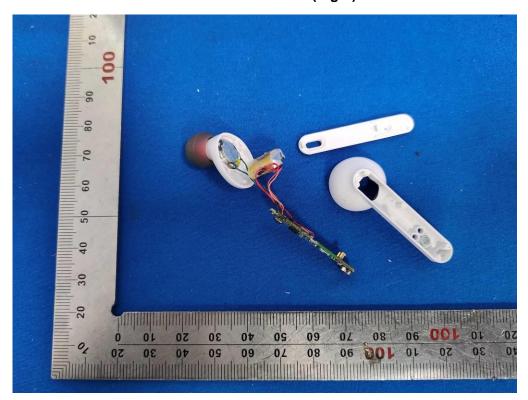


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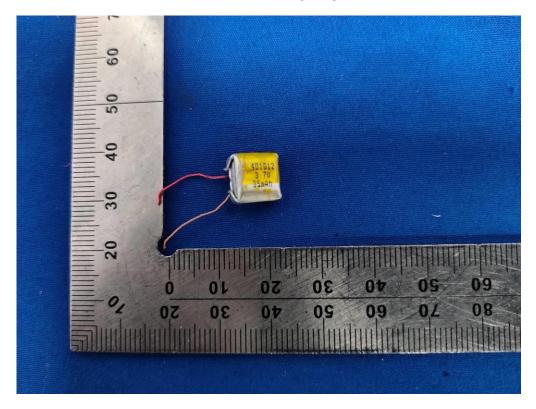


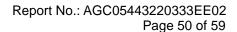


# OPEN VIEW OF EUT (Right)



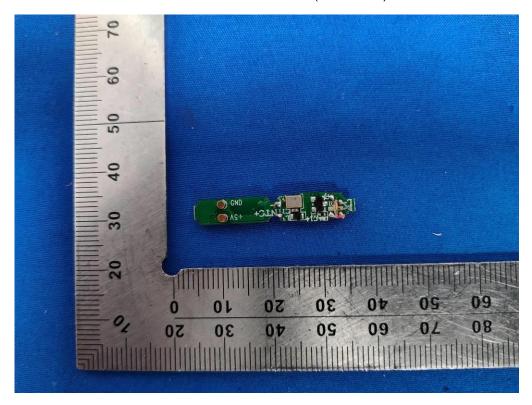
**BATTERY VIEW OF EUT** 



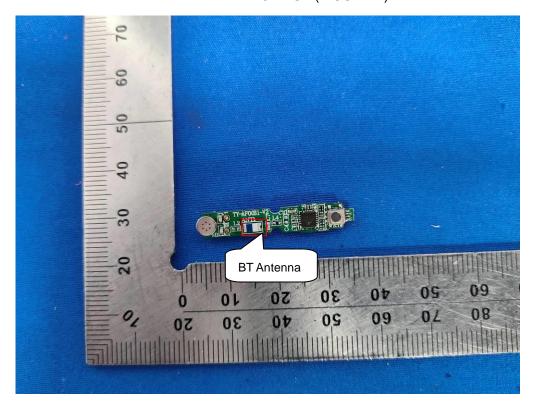




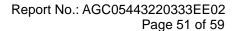
# INTERNAL VIEW OF EUT (FIGURE 1)



INTERNAL VIEW OF EUT (FIGURE 2)

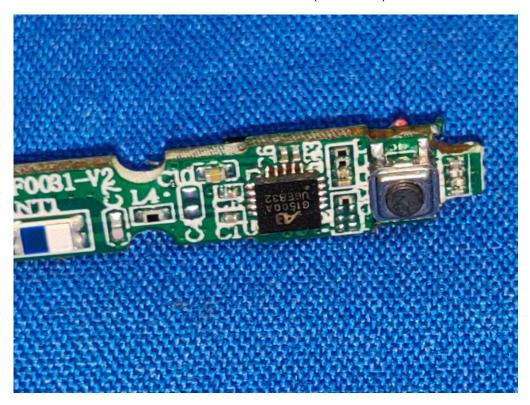


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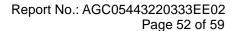


# INTERNAL VIEW OF EUT (FIGURE 3)



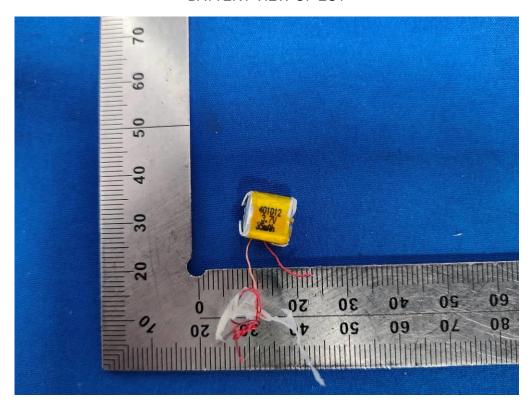
OPEN VIEW OF EUT (Left)



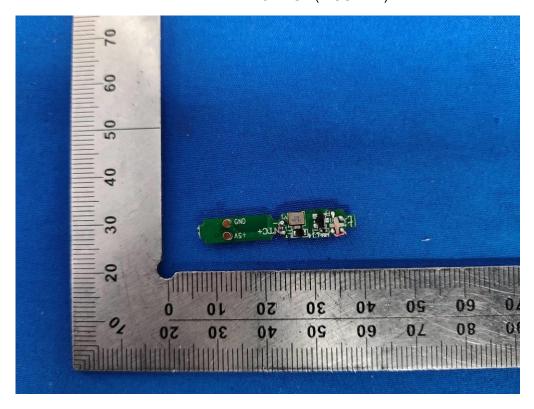




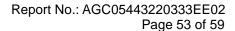
# **BATTERY VIEW OF EUT**



INTERNAL VIEW OF EUT (FIGURE 1)

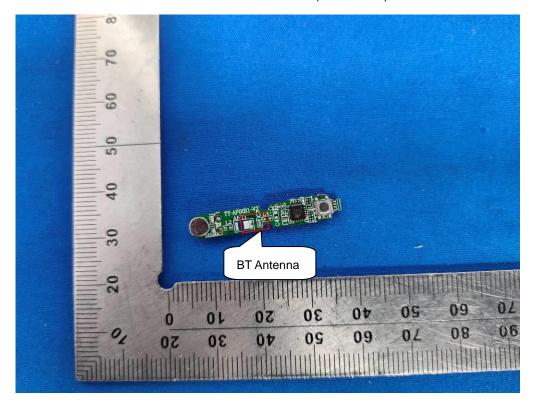


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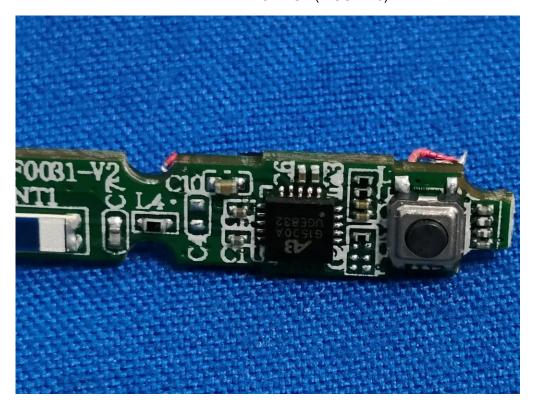




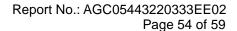
# INTERNAL VIEW OF EUT (FIGURE 2)



INTERNAL VIEW OF EUT (FIGURE 3)



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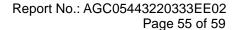
# TOP VIEW OF EUT (Charging Dock)



**BOTTOM VIEW OF EUT** 



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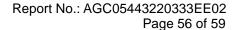
# FRONT VIEW OF EUT



**BACK VIEW OF EUT** 



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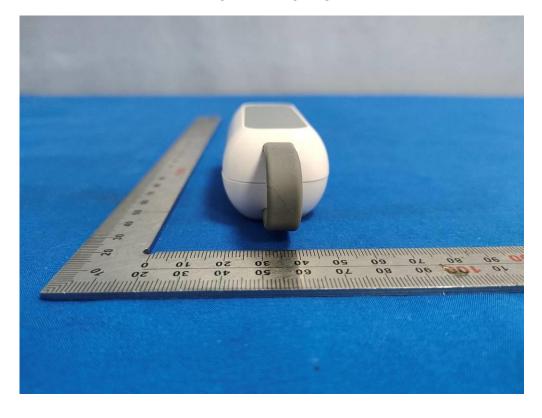


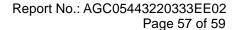


# **LEFT VIEW OF EUT**



RIGHT VIEW OF EUT





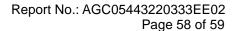


# PORT VIEW OF EUT



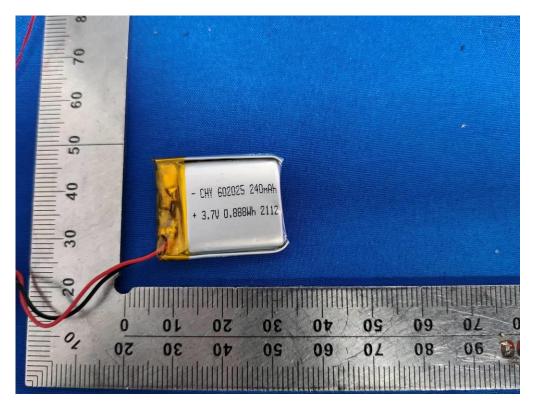
**OPEN VIEW OF EUT** 



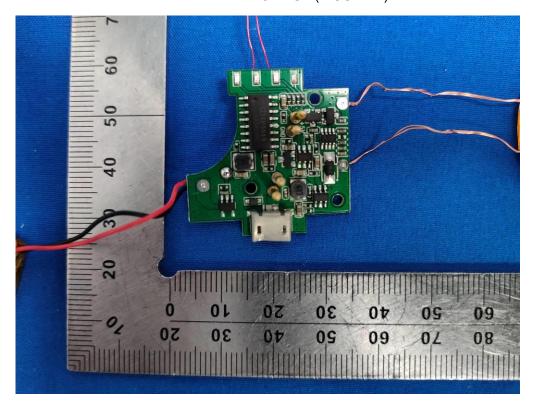


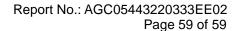


# **BATTERY VIEW OF EUT**



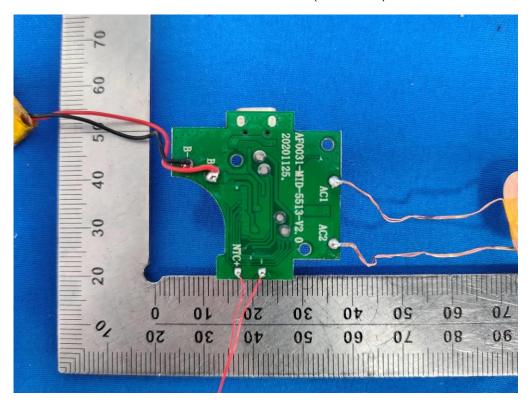
INTERNAL VIEW OF EUT (FIGURE 1)



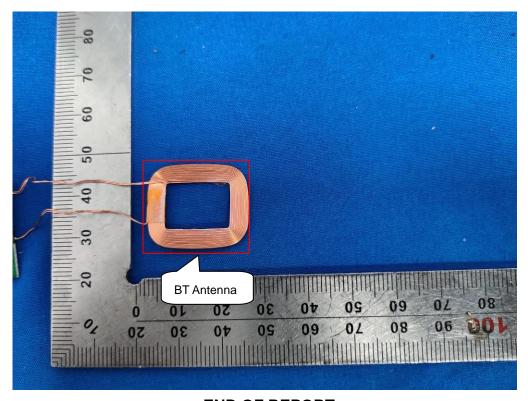




# INTERNAL VIEW OF EUT (FIGURE 2)



INTERNAL VIEW OF EUT (FIGURE 3)



# ----END OF REPORT----



# Conditions of Issuance of Test Reports

- 1. All samples and goods are accepted by the Attestation of Global Compliance (Shenzhen) Co., Ltd (the "Company") solely for testing and reporting in accordance with the following terms and conditions. The company provides its services on the basis that such terms and conditions constitute express agreement between the company and any person, firm or company requesting its services (the "Clients").
- 2. Any report issued by Company as a result of this application for testing services (the "Report") shall be issued in confidence to the Clients and the Report will be strictly treated as such by the Company. It may not be reproduced either in its entirety or in part and it may not be used for advertising or other unauthorized purposes without the written consent of the Company. The Clients to whom the Report is issued may, however, show or send it, or a certified copy thereof prepared by the Company to its customer, supplier or other persons directly concerned. The Company will not, without the consent of the Clients, enter into any discussion or correspondence with any third party concerning the contents of the Report, unless required by the relevant governmental authorities, laws or court orders.
- 3. The Company shall not be called or be liable to be called to give evidence or testimony on the Report in a court of law without its prior written consent, unless required by the relevant governmental authorities, laws or court orders.
- 4. In the event of the improper use of the report as determined by the Company, the Company reserves the right to withdraw it, and to adopt any other additional remedies which may be appropriate.
- 5. Samples submitted for testing are accepted on the understanding that the Report issued cannot form the basis of, or be the instrument for, any legal action against the Company.
- 6. The Company will not be liable for or accept responsibility for any loss or damage however arising from the use of information contained in any of its Reports or in any communication whatsoever about its said tests or investigations.
- 7.Clients wishing to use the Report in court proceedings or arbitration shall inform the Company to that effect prior to submitting the sample for testing.
- 8. The Company is not responsible for recalling the electronic version of the original report when any revision is made to them. The Client assumes the responsibility to providing the revised version to any interested party who uses them.
- 9. Subject to the variable length of retention time for test data and report stored hereinto as otherwise specifically required by individual accreditation authorities, the Company will only keep the supporting test data and information of the test report for a period of six years. The data and information will be disposed of after the aforementioned retention period has elapsed. Under no circumstances shall we provide any data and information which has been disposed of after retention period. Under no circumstances shall we be liable for damage of any kind, including (but not limited to) compensatory damages, lost profits, lost data, or any form of special, incidental, indirect, consequential or punitive damages of any kind, whether based on breach of contract of warranty, tort (including negligence), product liability or otherwise, even if we are informed in advance of the possibility of such damages.